The Abdus Salam International Centre for Theoretical Physics

2384-12

ICTP Latin-American Advanced Course on FPGADesign for Scientific Instrumentation

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FPGA applications in High Energy Physics

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FPGA applications in High Energy Physics

Alexander Kluge

CERN

Outline

CERN – electronics system concepts

a project cycle

Application: Data selection

Application: Data processing

CERN

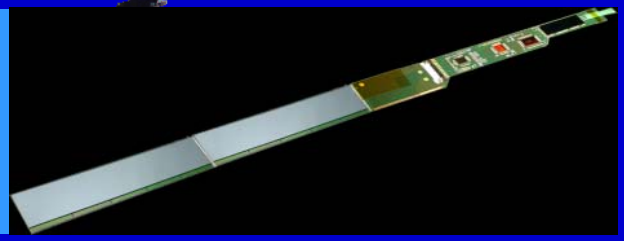
Application overview CERN

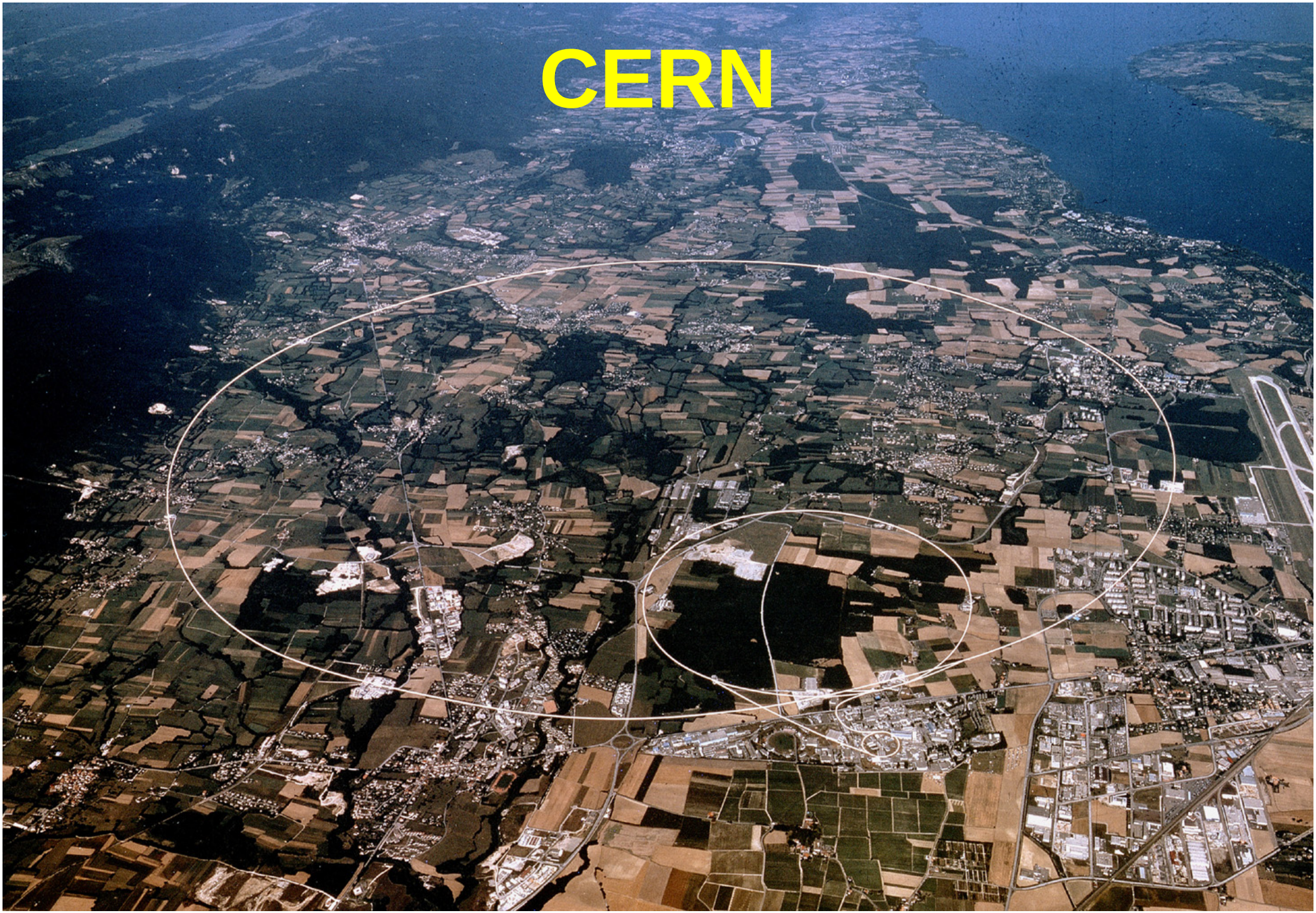
CERN, experiments

- Aim
- General detector concept
- Examples

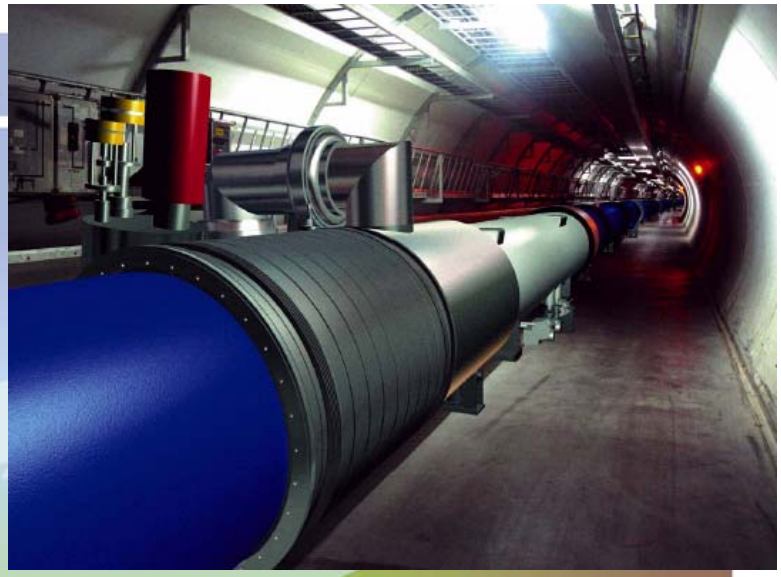
Principle of data acquisition & data flow

data selection: trigger
data processing




CERN

Overall view of the LHC experiments.



GENEVE

LHC - B
Point 8

CERN

ATLAS
Point 1

ALICE
Point 2

CMS
Point 5

SPS

TI 8

TI 2

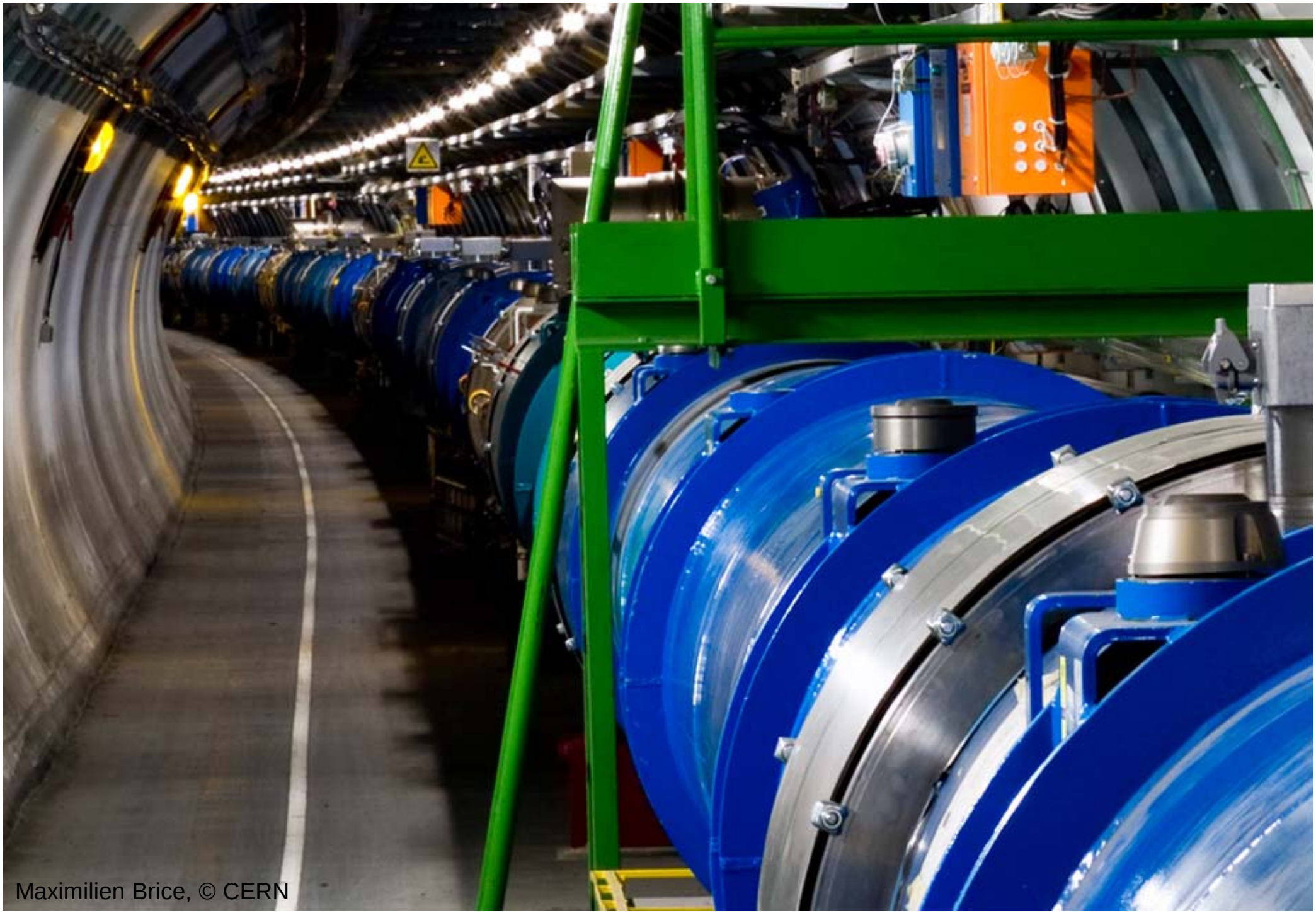
LHC - B

ATLAS

ALICE

CMS

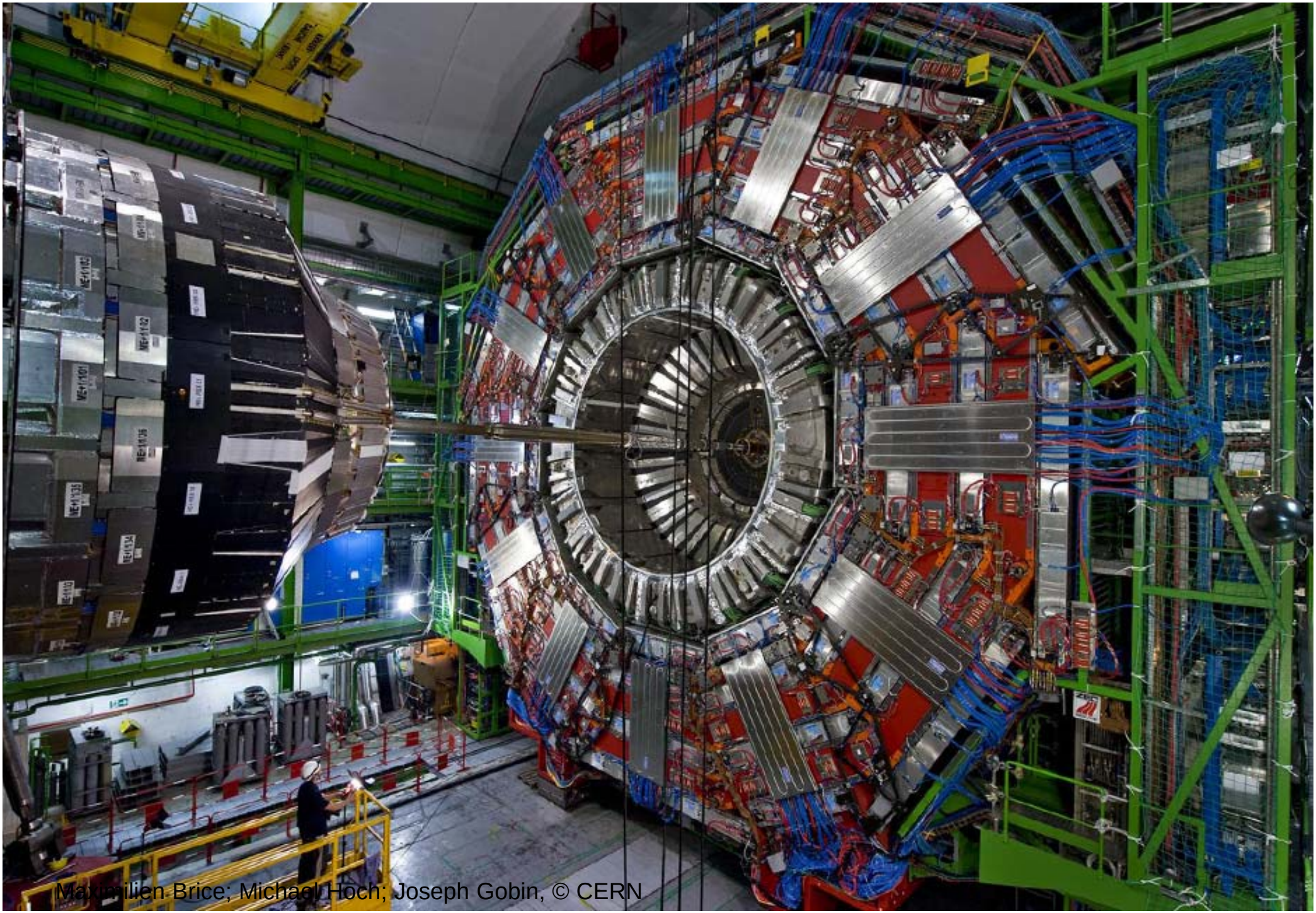
LEP/LHC


Maximilien Brice, © CERN

LHC in 10 minutes

Experiments

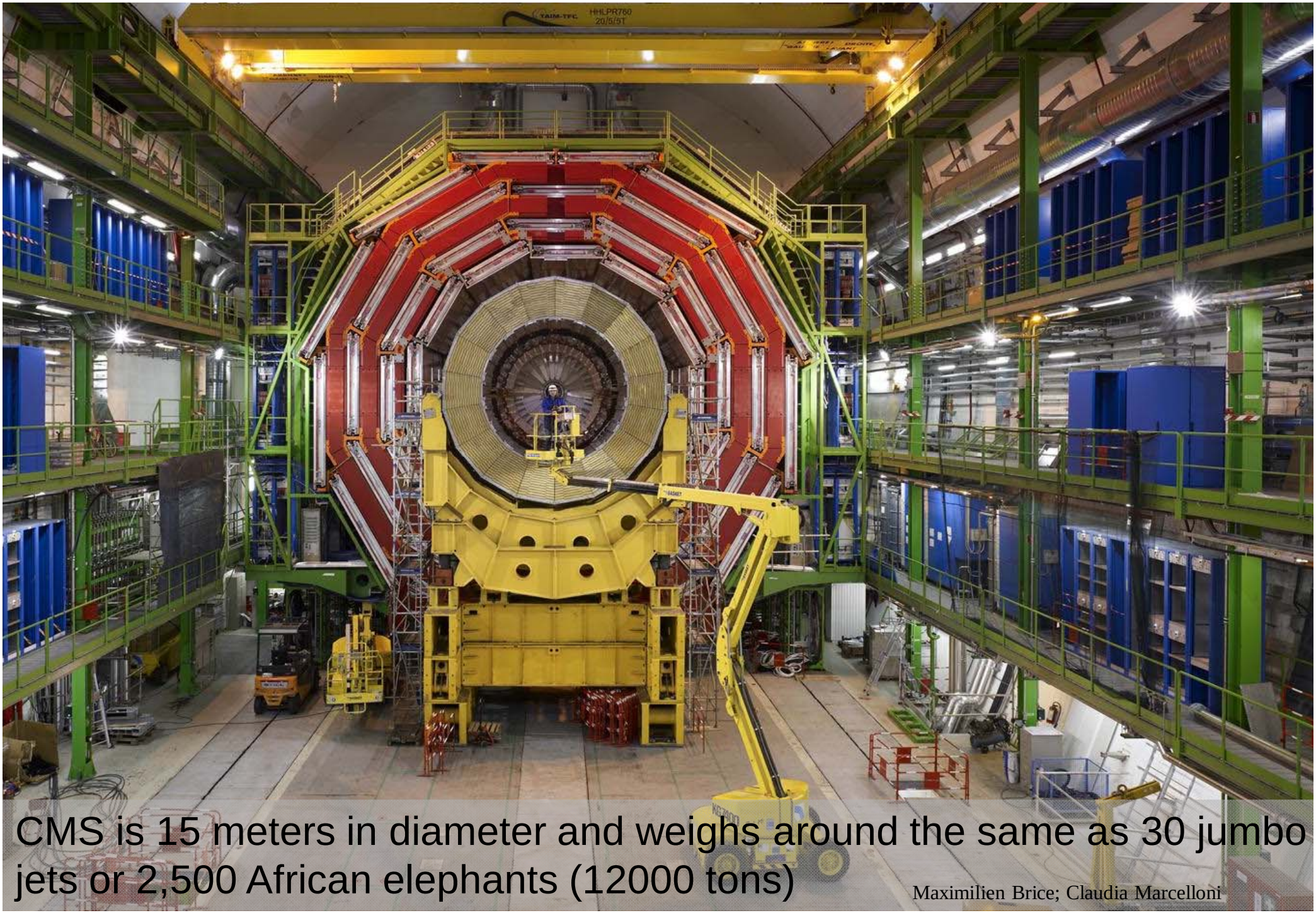

Maximilien Brice, © CE



Maximilien Brice; Michael Hoch; Joseph Gobin, © CERN

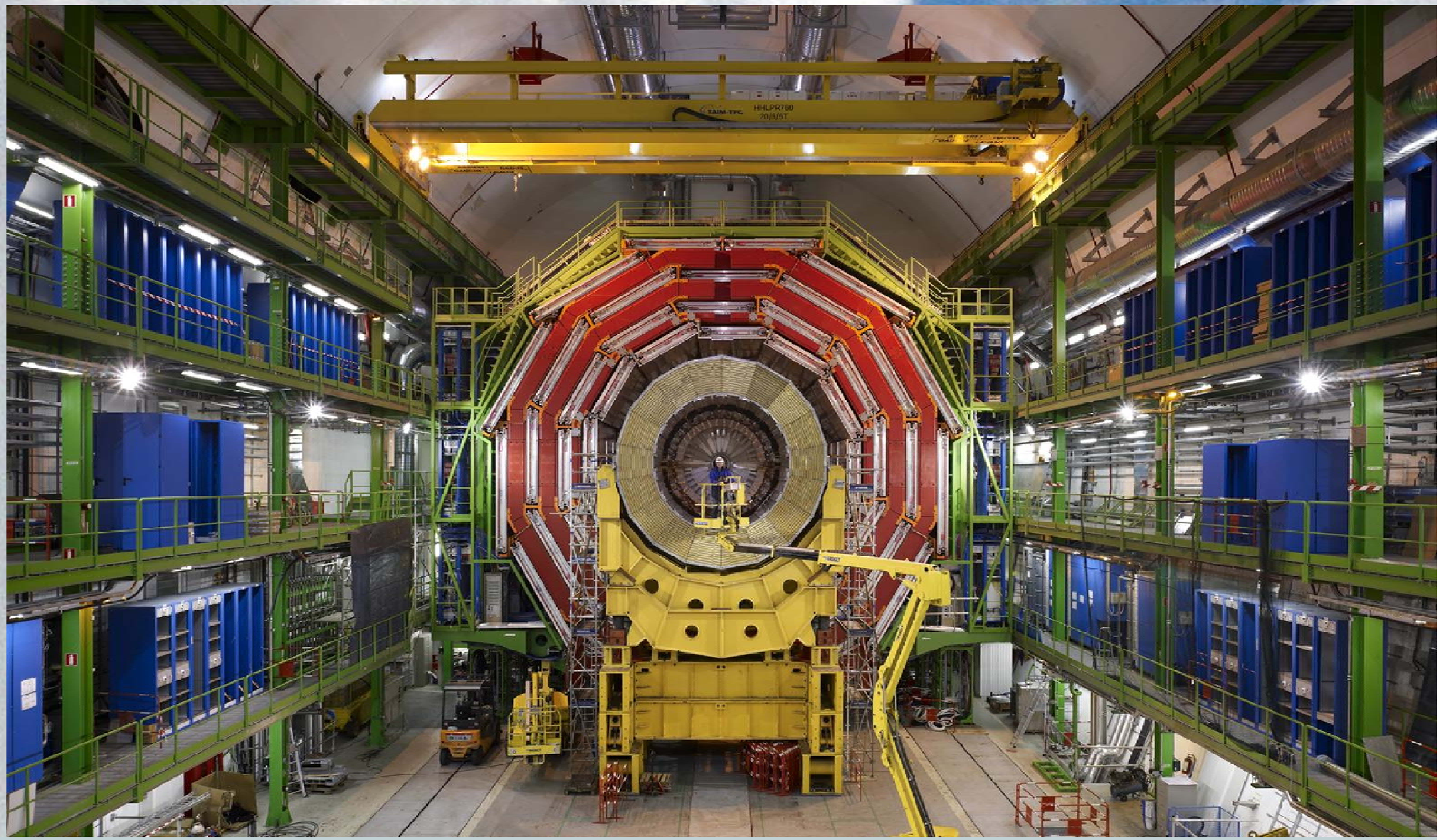
Sensor system

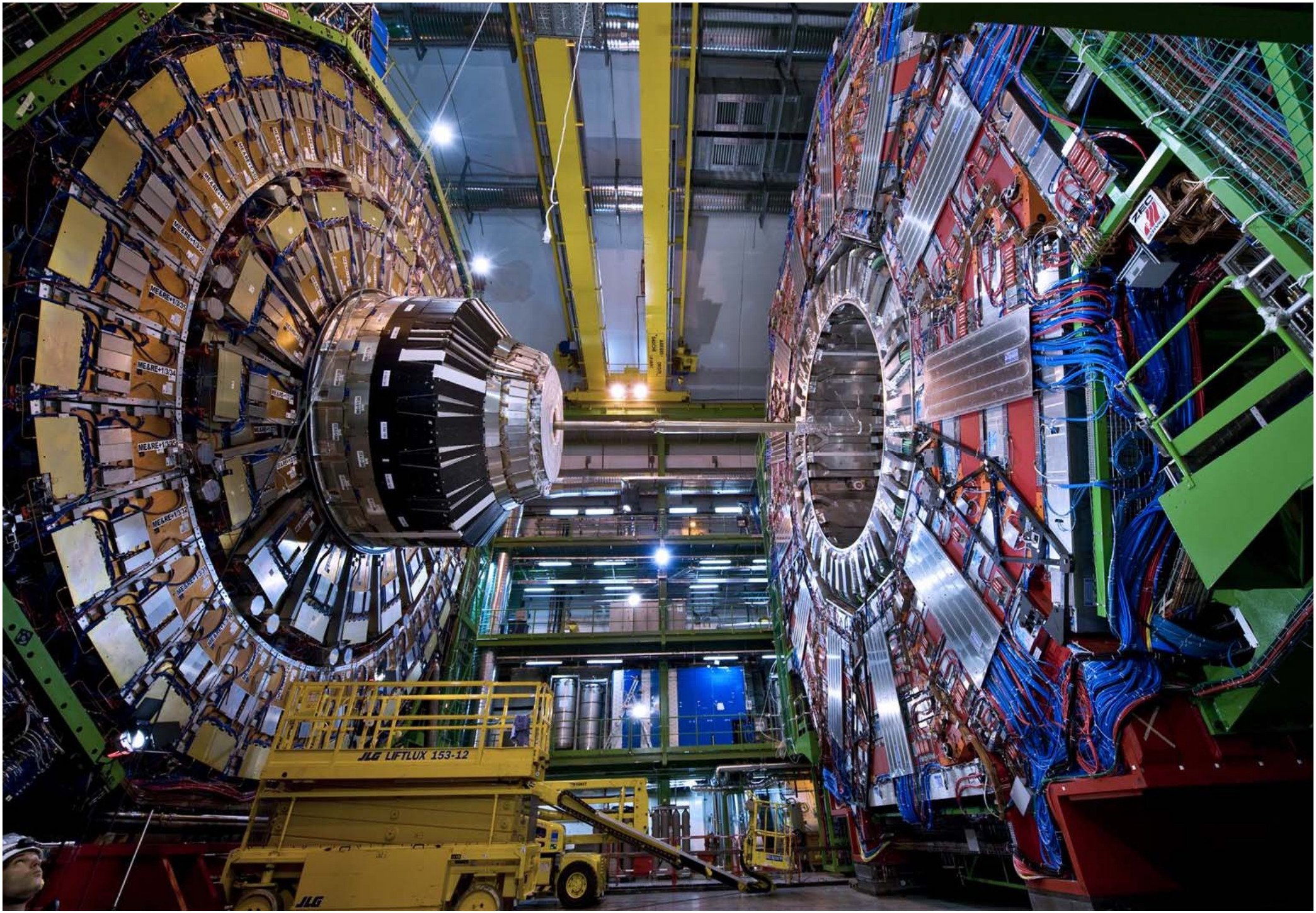
Huge sensor system distributed over 100s of meters:
Sensor
sensor read-out electronics
data transmission
data processing
data analysis
display
cooling
mechanics



CMS is 15 meters in diameter and weighs around the same as 30 jumbo jets or 2,500 African elephants (12000 tons)

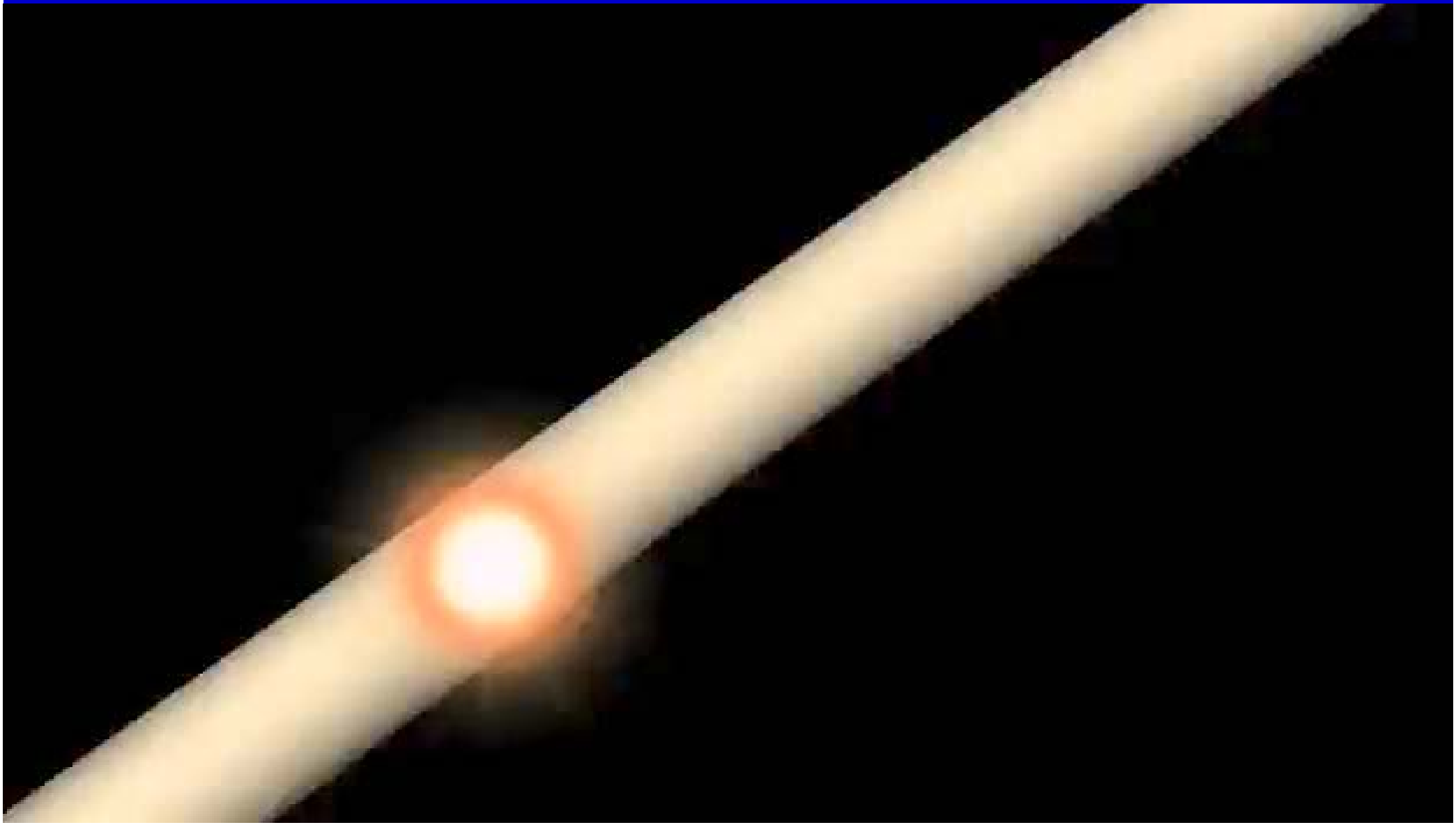
Maximilien Brice; Claudia Marcelloni



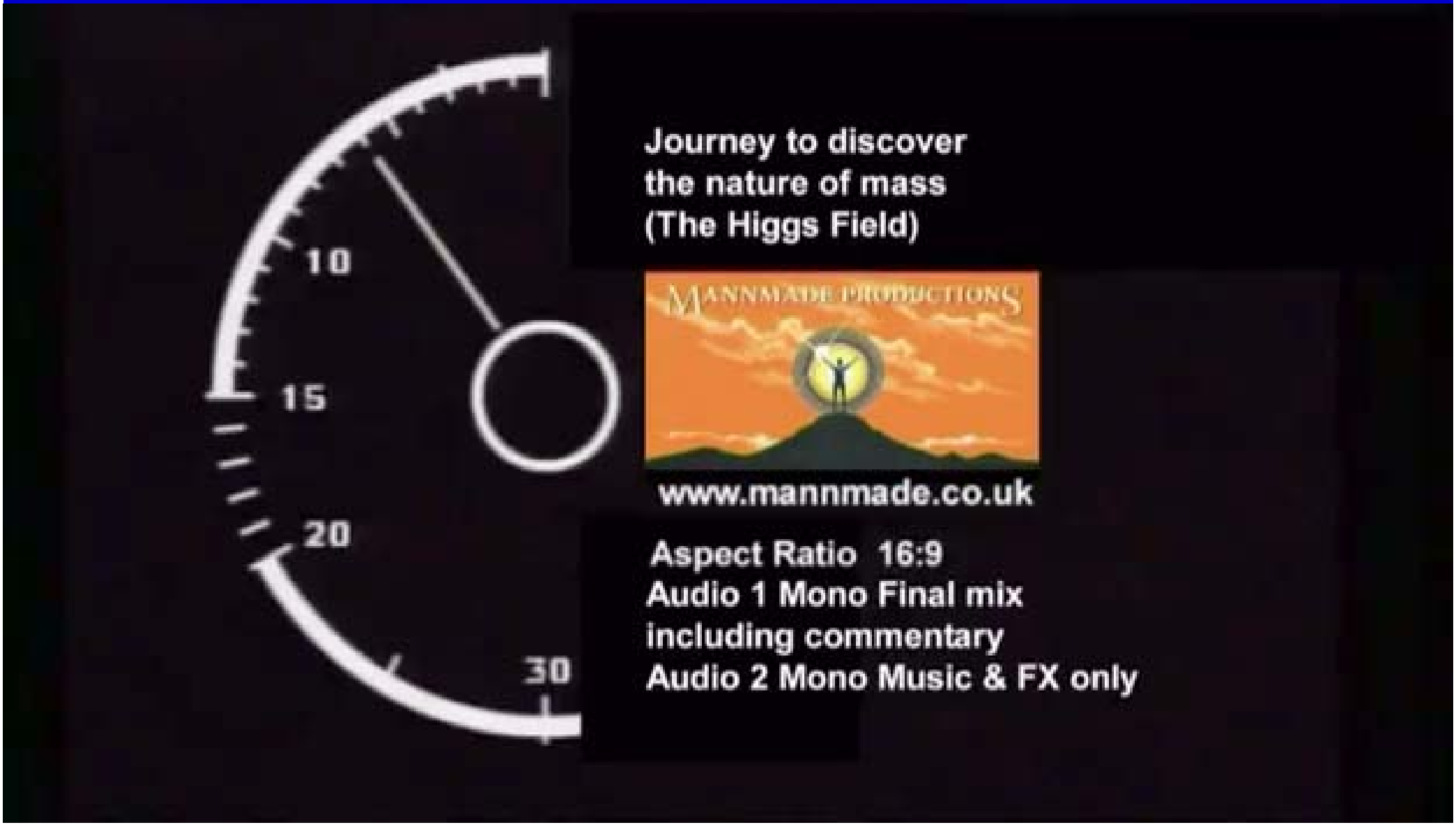

JLG LIFTLUX 153-12
JLG


Peter Ginter, © CERN

LHC & ATLAS event



Higgs field


10
15
20
30
Journey to discover
the nature of mass
(The Higgs Field)
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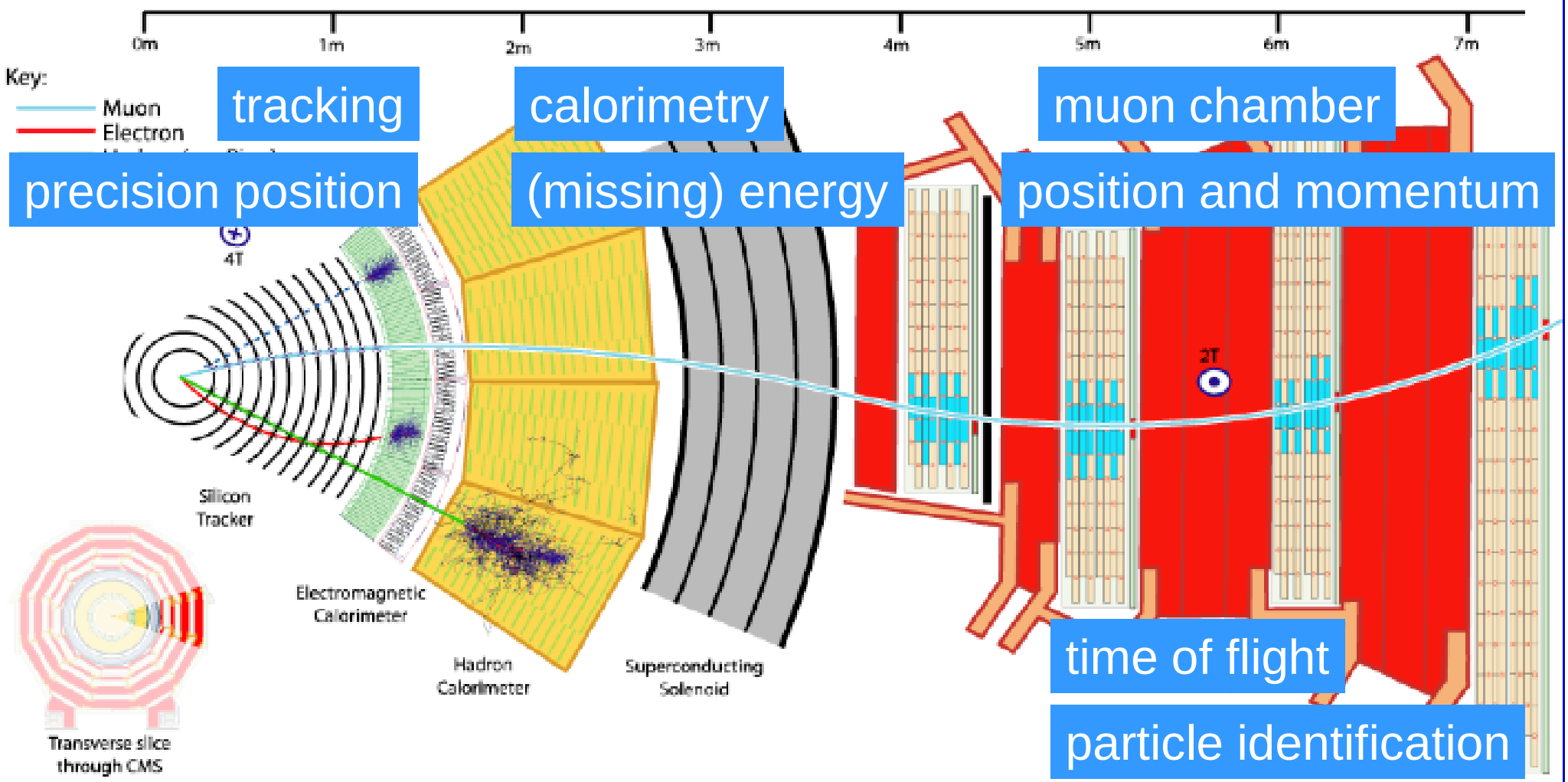
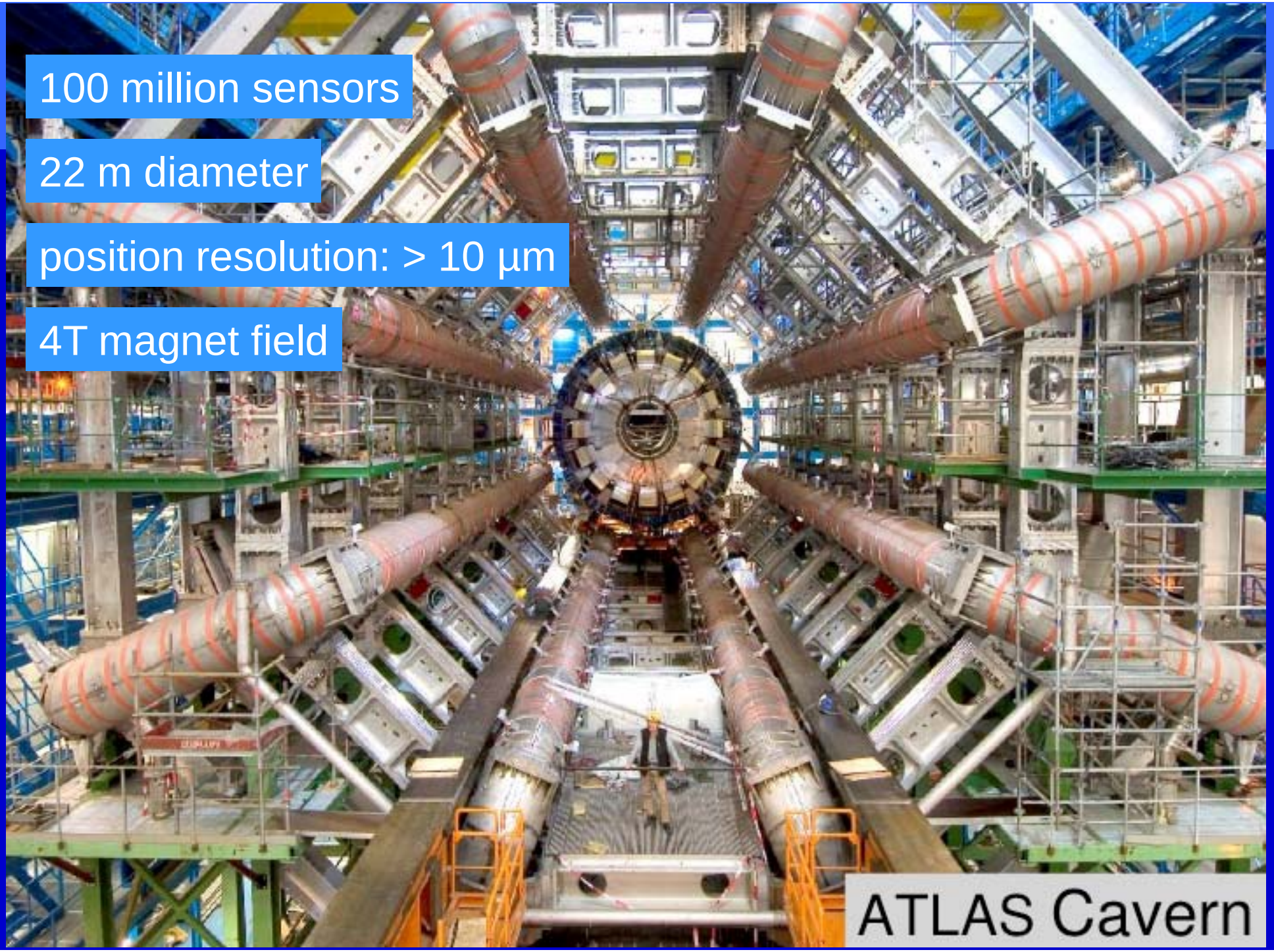
Aspect Ratio 16:9
Audio 1 Mono Final mix
including commentary
Audio 2 Mono Music & FX only

Principle of detectors

Detector: ALICE

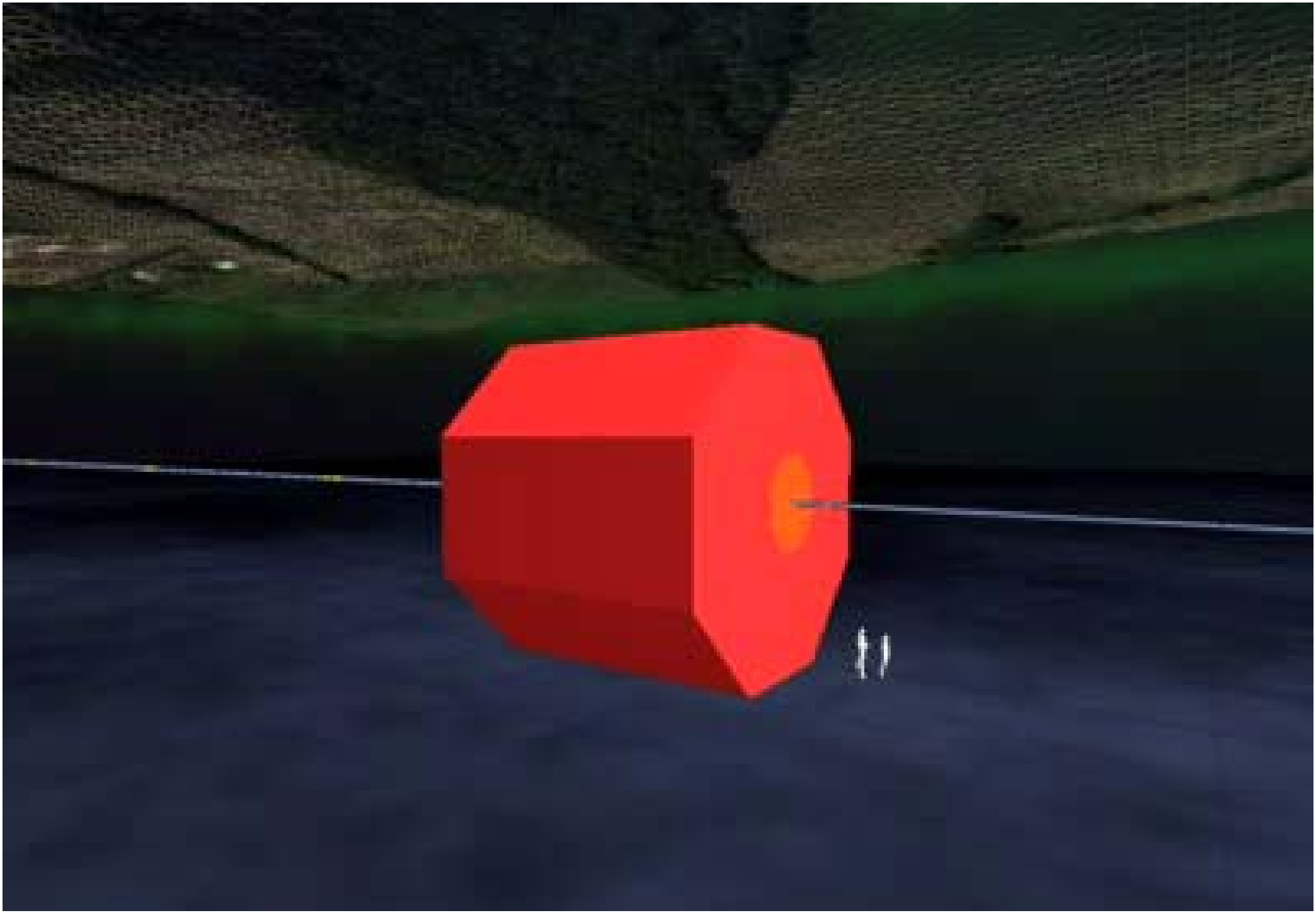
Principle of detectors




100 million sensors
22 m diameter
position resolution: > 10 μm
4T magnet field
ATLAS Cavern

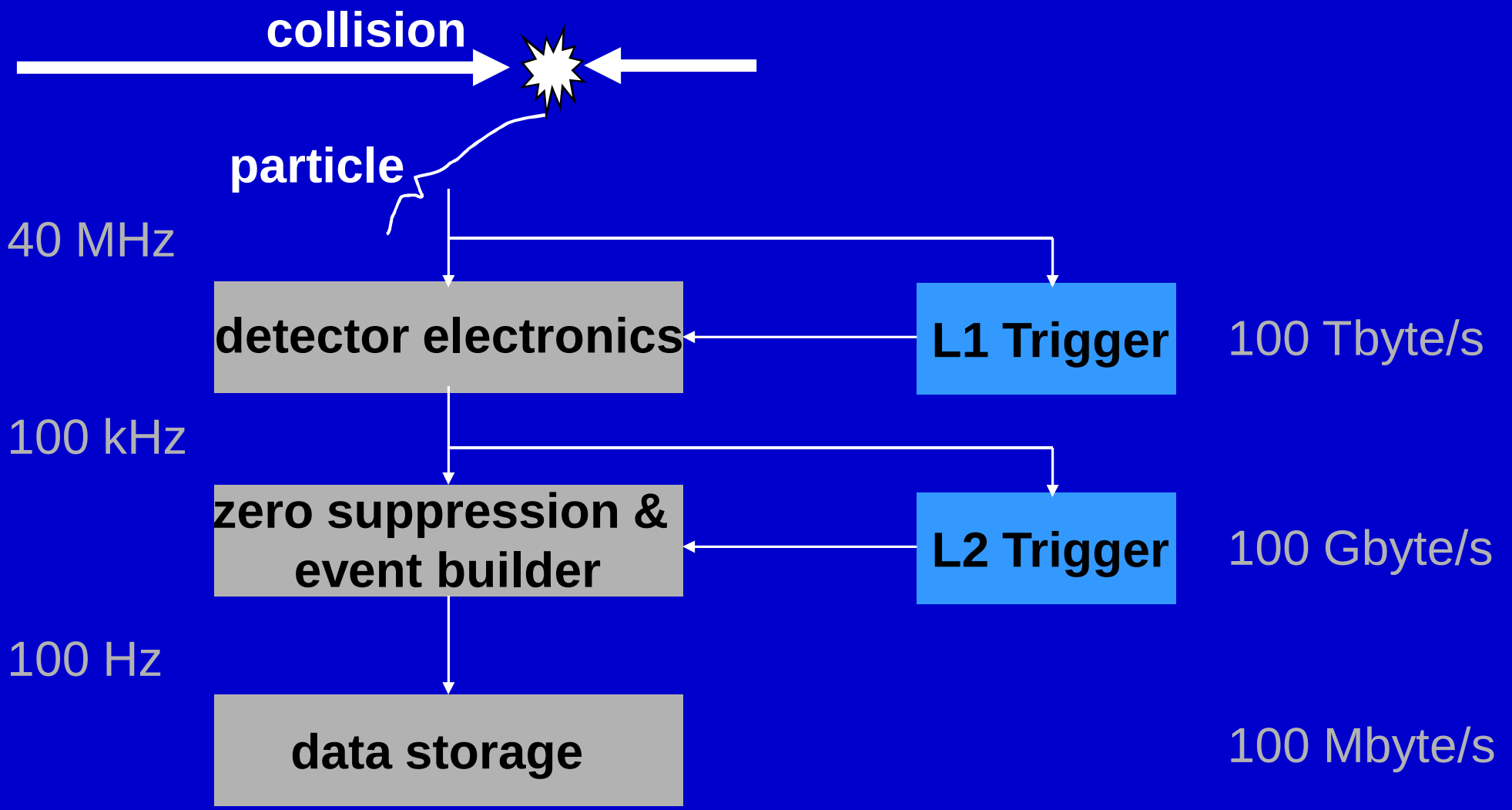
Detector: ALICE

Detector: ALICE

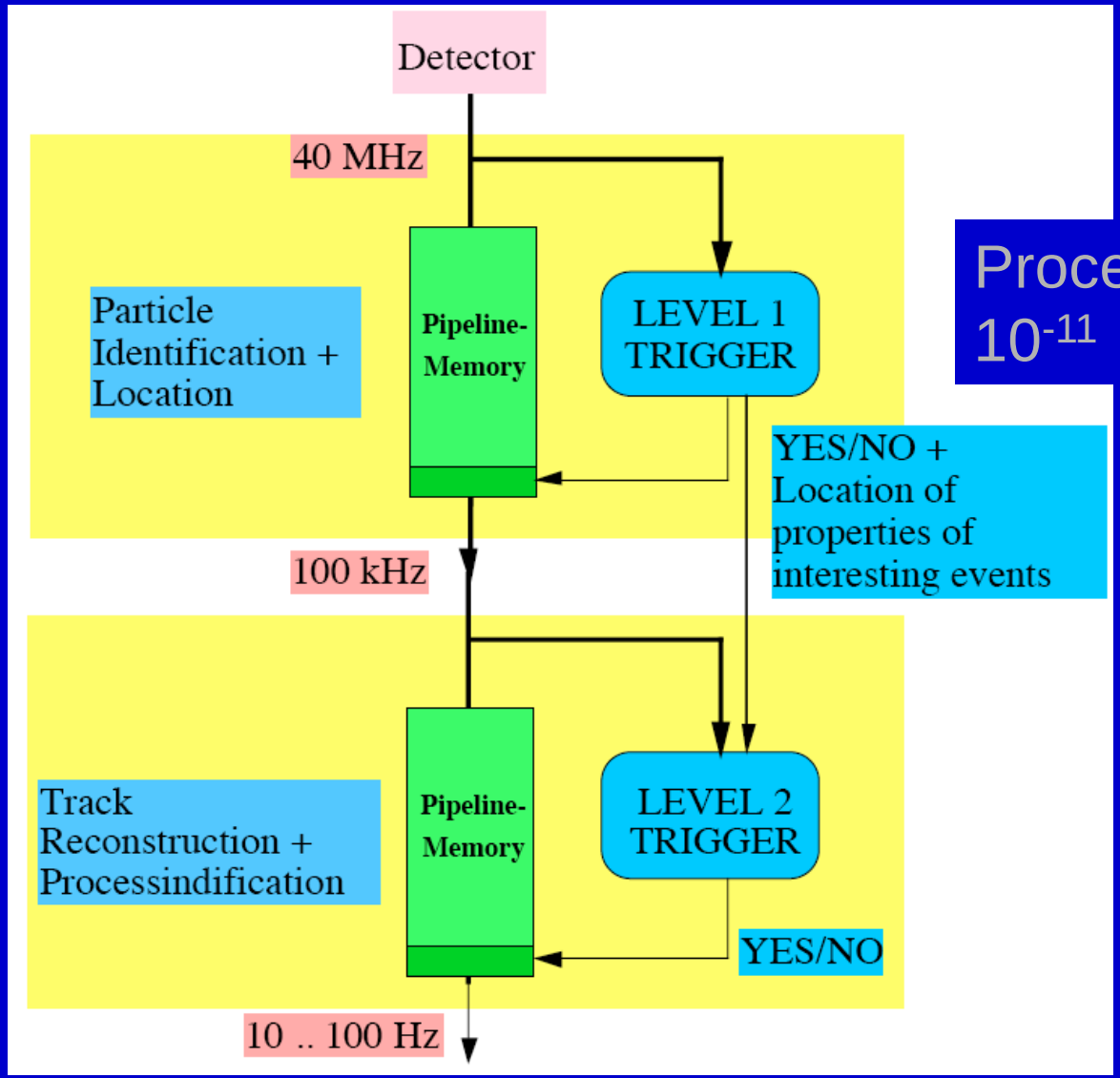


Principle of Data acquisition

Data selection



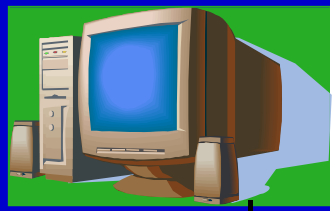
Data selection



Process probability 10^{-11}

Principle of data acquisition

Data selection: trigger - FPGA



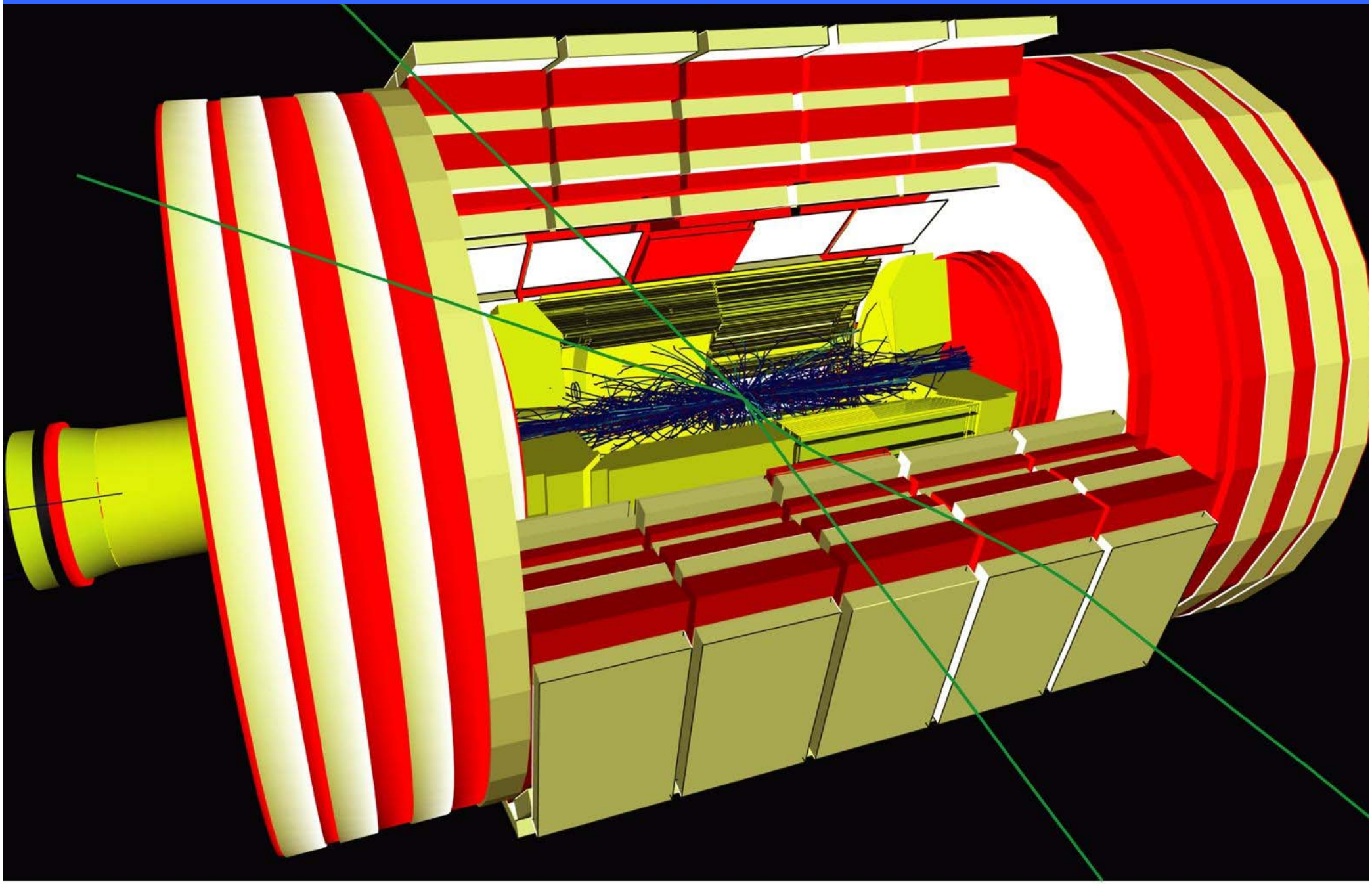
Front end: data taking-ASICs

Read out electronics-FPGA

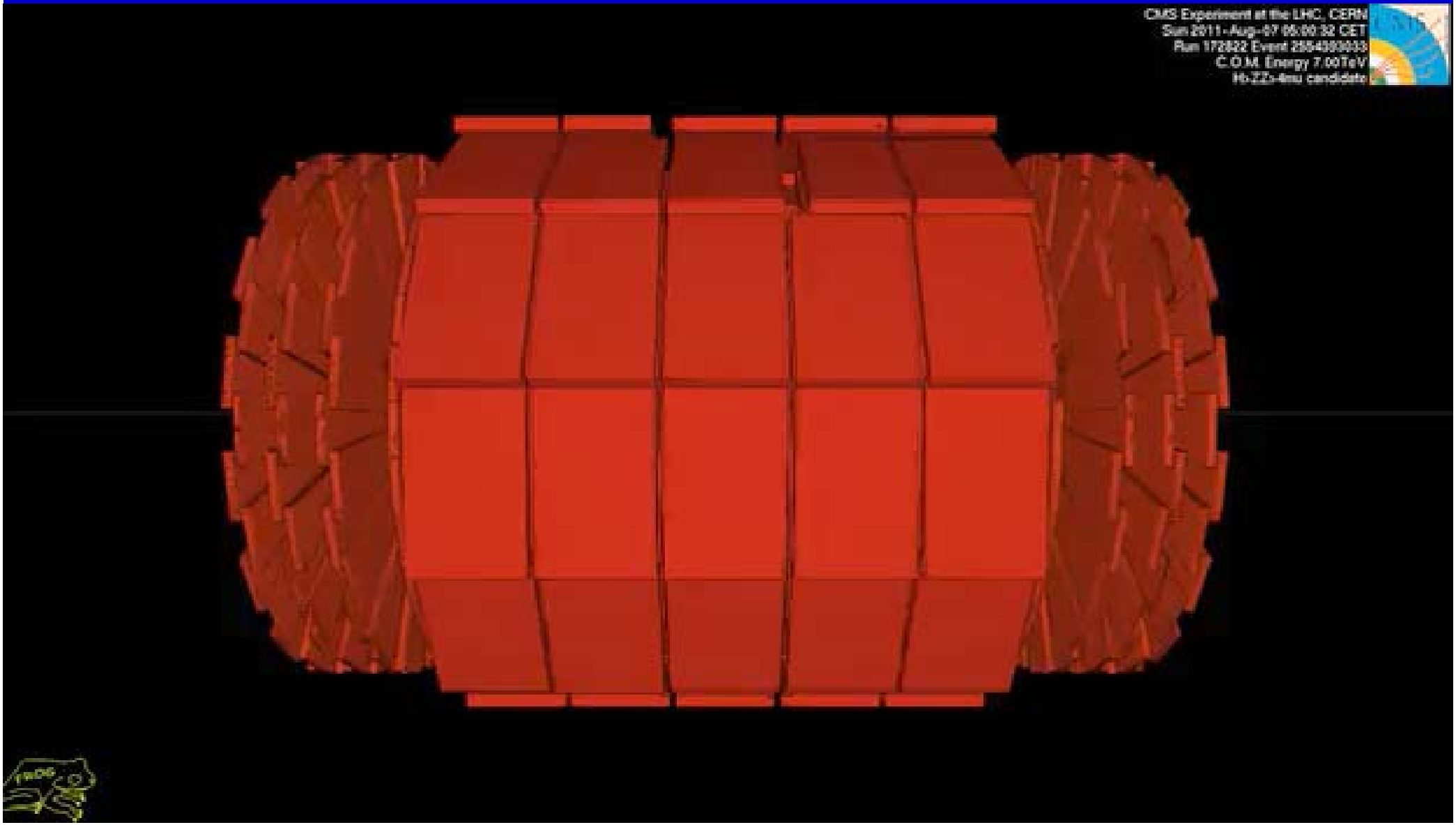
Claudia Marcelloni, Maximilien Brice, © CERN

Trigger processor

Simulation of a decay: Higgs to four muons in CMS



Higgs to four muons



Challenge/Specifications

- **Fast**
  - the faster, the less data needs to be pipelined/stored
- **Compact**
  - Many data channels are going into one processor system
- **Connectivity**
  - High number
  - Transmission delay on cables (5ns/m -> 200 m -> 1µs)
- **Reliability**
  - Physics processes with a probability of 10^{-11} need to recorded
  - Processing and data transmission error rate >> 10^{-11}

Challenge/Specifications

- **Quality control**
  - Processes are verified in hardware and software processors
- **Radioactive environment**
- **Data volume/rate**
  - Many (100.000) parallel inputs in 25 ns intervall
- **Parallel processing – pipelined processing**
  - FPGA
  - highly parallel because of many IOs and interconnectability

Challenge/Specifications

Example: Tracal Trigger

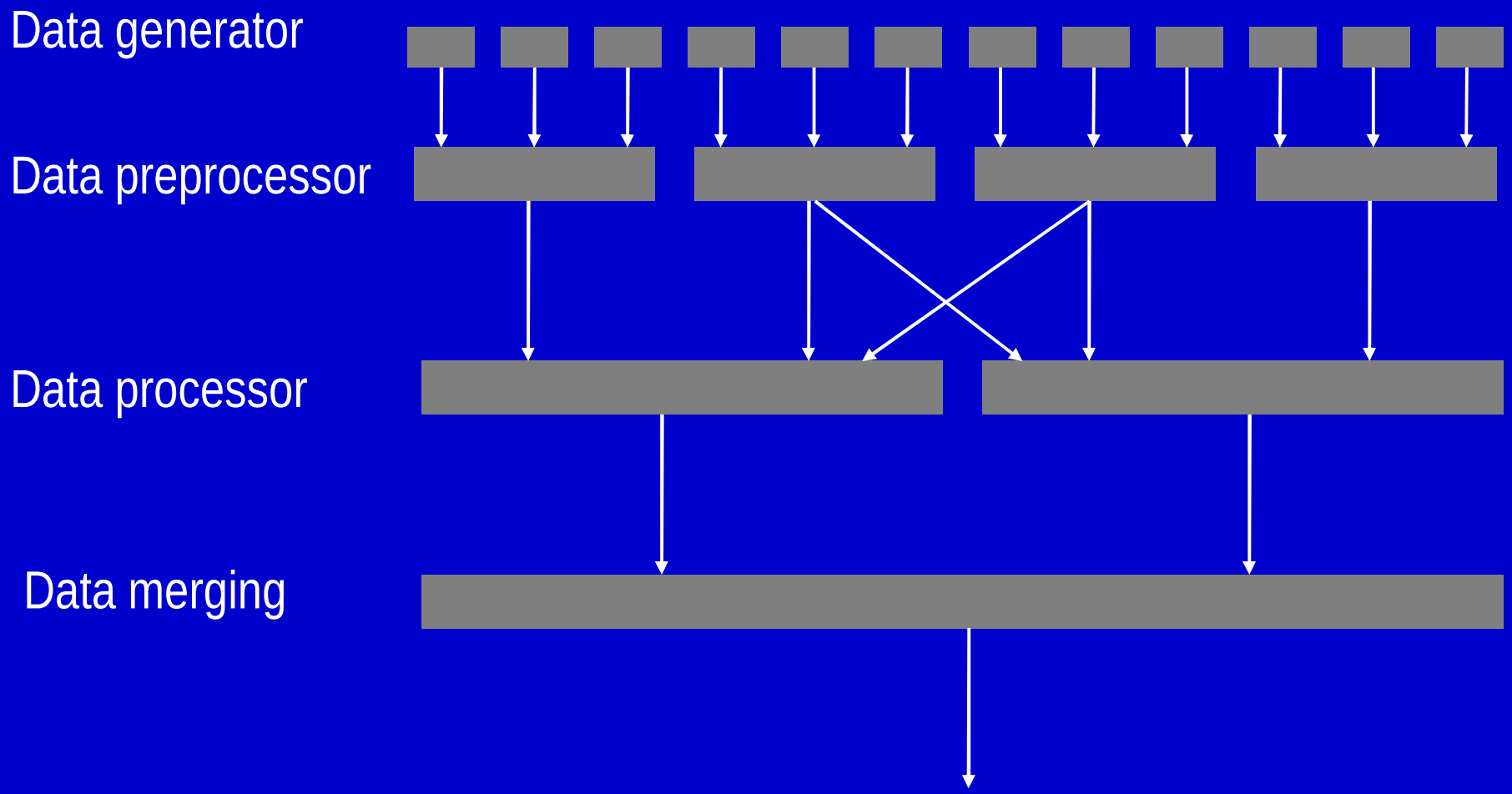
- Specifications
  - Calculate how many out of 1000 binary sensor inputs are active
  - Each 25 ns a new set of 1000 bits
  - Result required within 100 ns
- Solution possibilities
- Today and 10 years ago

Challenge/Specifications

System topology

- **high number of inputs ->**
  - operation to simplify data and reduce data amount
- **reduced number of inputs ->**
  - connected to more complex processing units
- **at the end of processing chain ->**
  - interest to integrate as much information into 1 FPGA to reduce interconnection

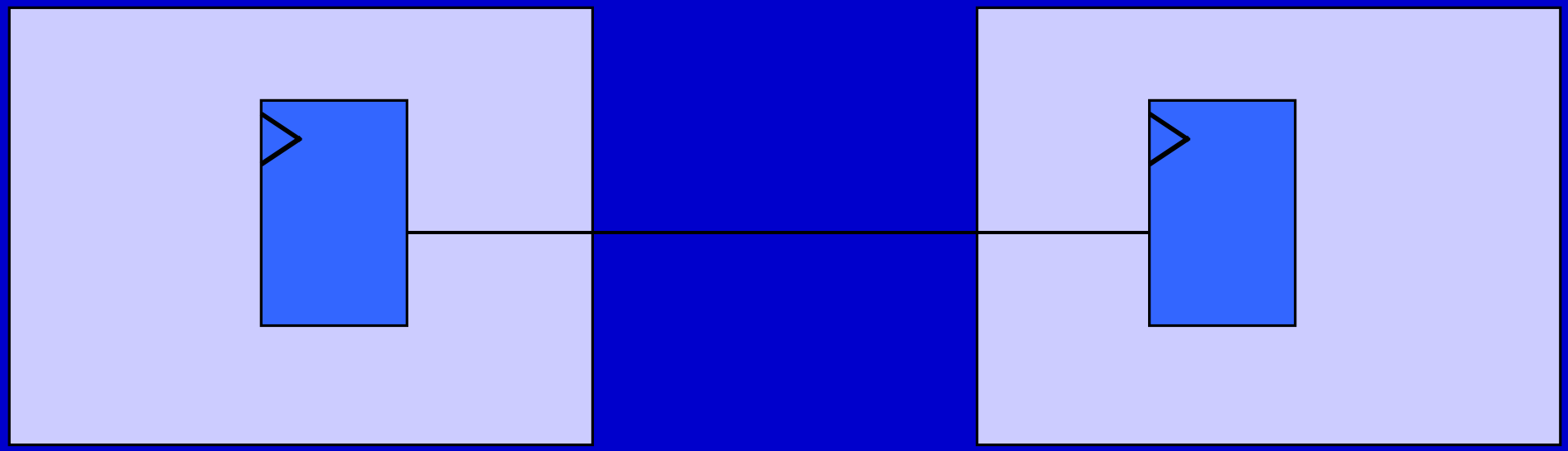
Data funnel


Data generator
Data preprocessor
Data processor
Data merging

Challenge/Specifications

System topology: Interconnection:

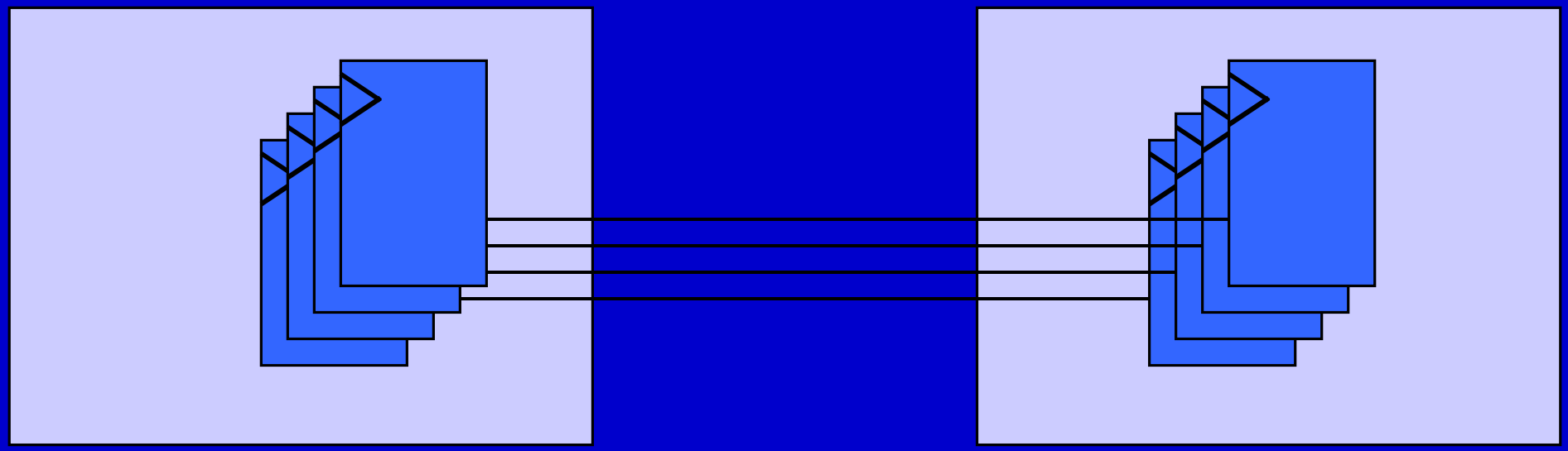
- **delay**
  - (clock to pin, transmission outside FPGA, setup time)



Challenge/Specifications

System topology: Interconnection:

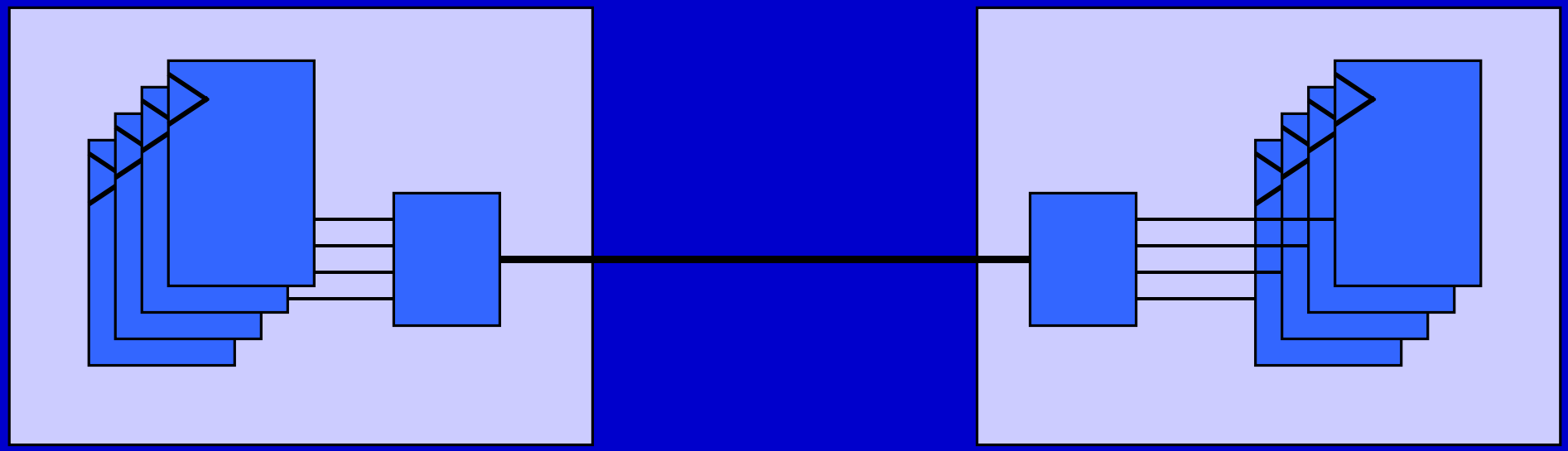
- **Parallel interconnection:**
  - high number of IOs, problem moved to board level
  - reliability impact due to solder joints or connectors



Challenge/Specifications

System topology: Interconnection:

- **Serial interconnections at high speed**
  - reduce reliability impact and increases delay (trigger needs to be fast)



Challenge/Specifications

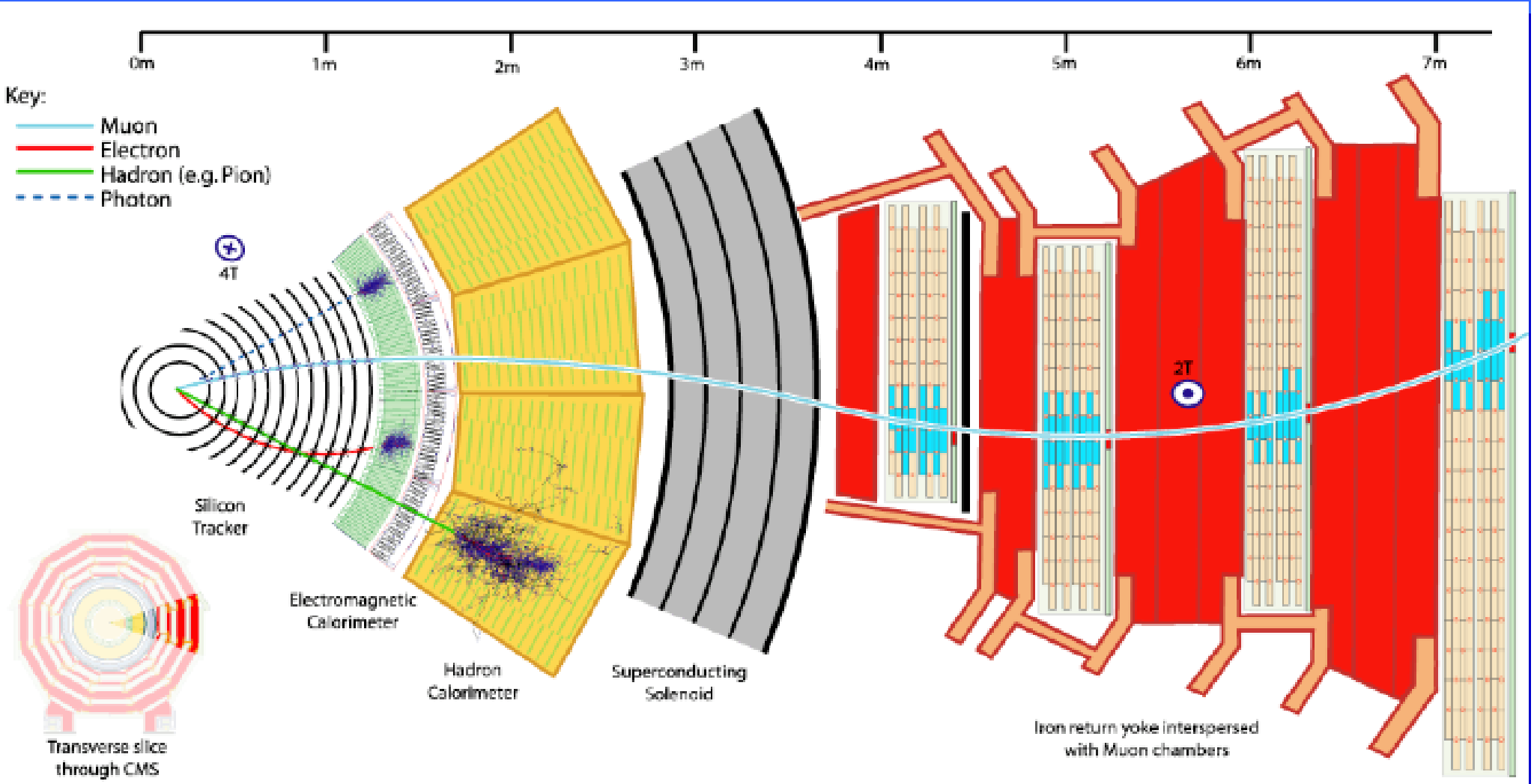
System topology: Interconnection:

- **delay**
  - (clock to pin, transmission outside FPGA, setup time)
- **Parallel interconnection:**
  - high number of IOs, problem moved to board level
  - reliability impact due to solder joints or connectors
- **Serial interconnections at high speed**
  - reduce reliability impact but increase delay (trigger needs to be fast)

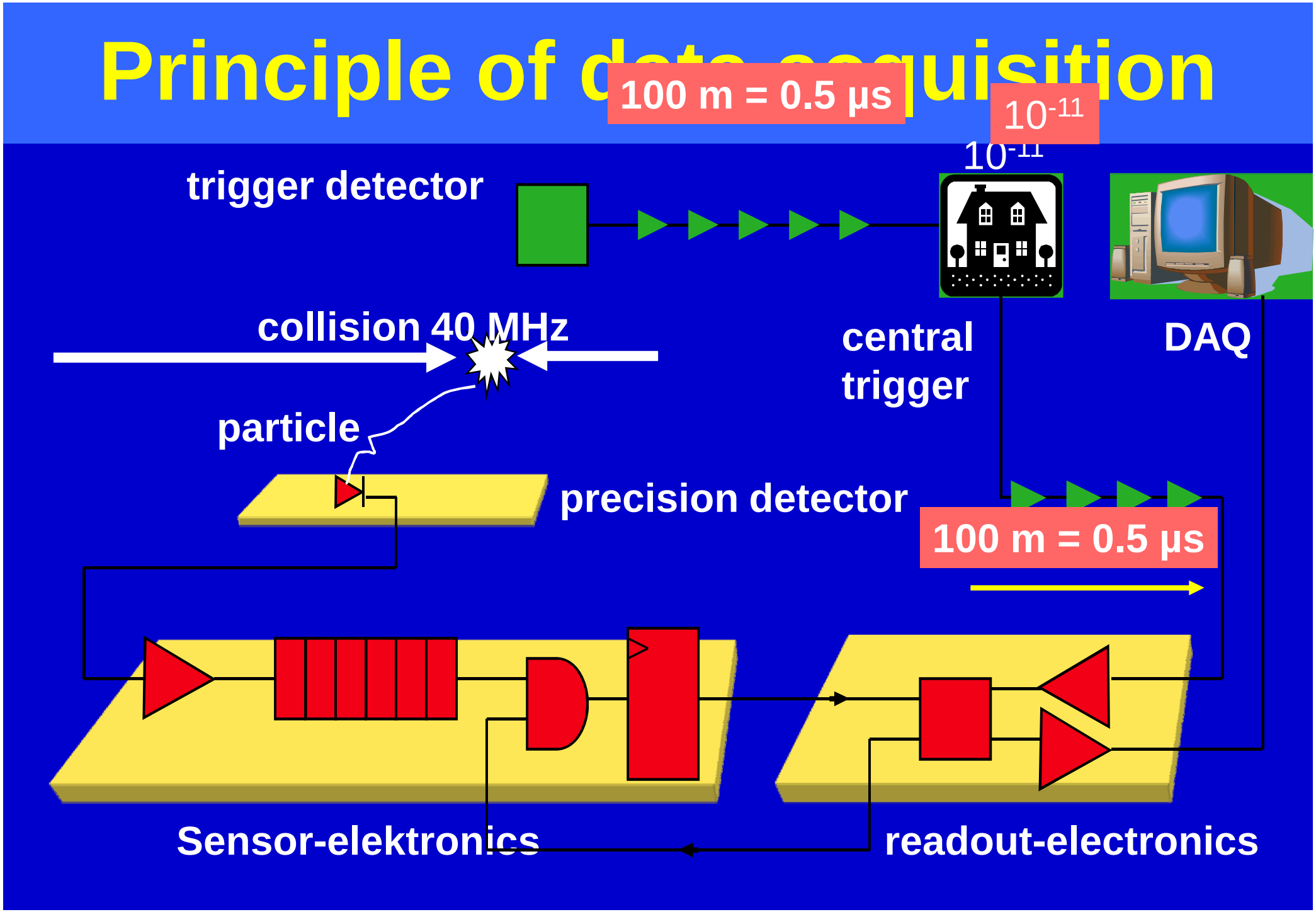
- **Interest to keep as much as possible within the same FPGA**

Muon Track Finder Trigger Processor

Muon track finder trigger



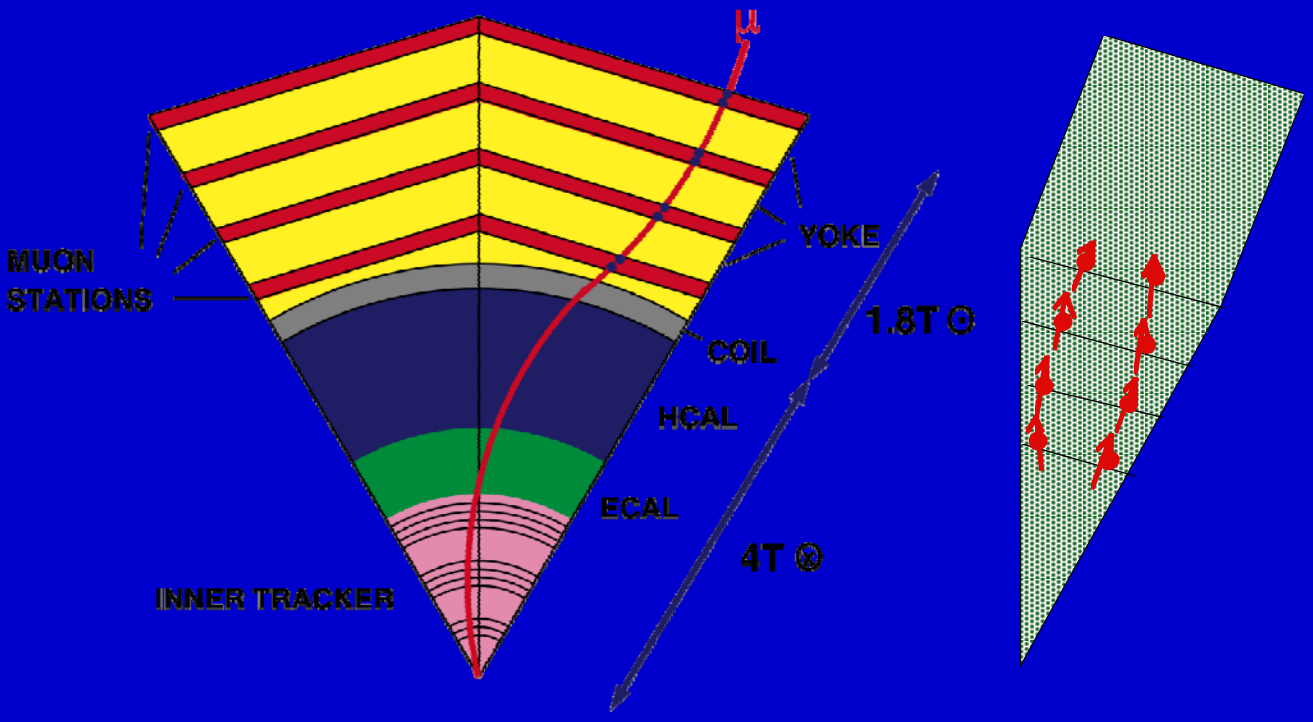
Principle of data acquisition

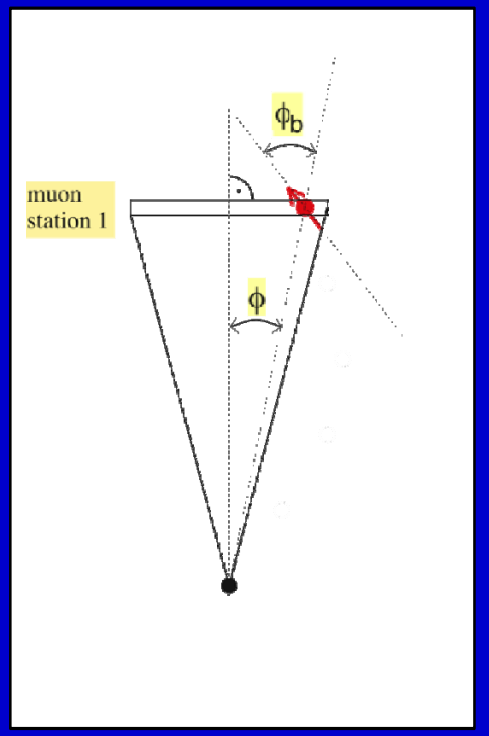


Muon track finder trigger

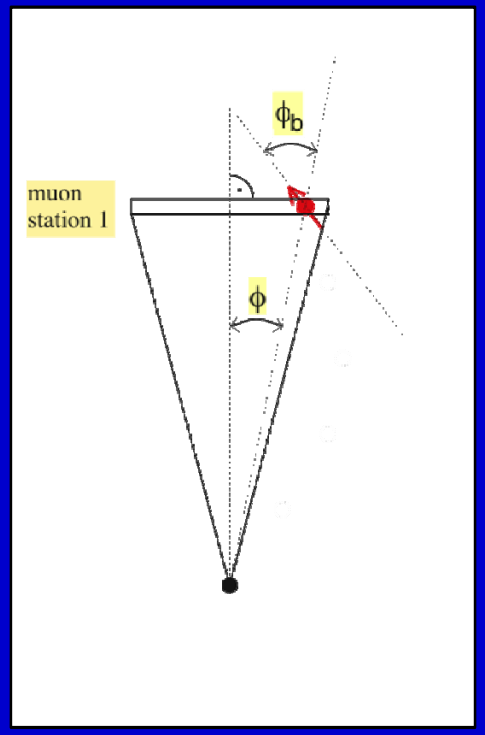
- **Size of detector system**
  - r = 14 m, length = 20 m
    - cable delay ~ 5 ns/m -> synchronisation
- **Each 25 ns new data set**
- **240 detector modules – 200.000 detector cells**
- **Identify particles (muons)**
- **Measure curvature = momentum of particles within 400 ns**
- **Find 4 particles with highest momentum**

Muon track finder trigger





Muon track finder trigger



200.000 sensors ->

240 chambers x 2 track segments =
480 track segments

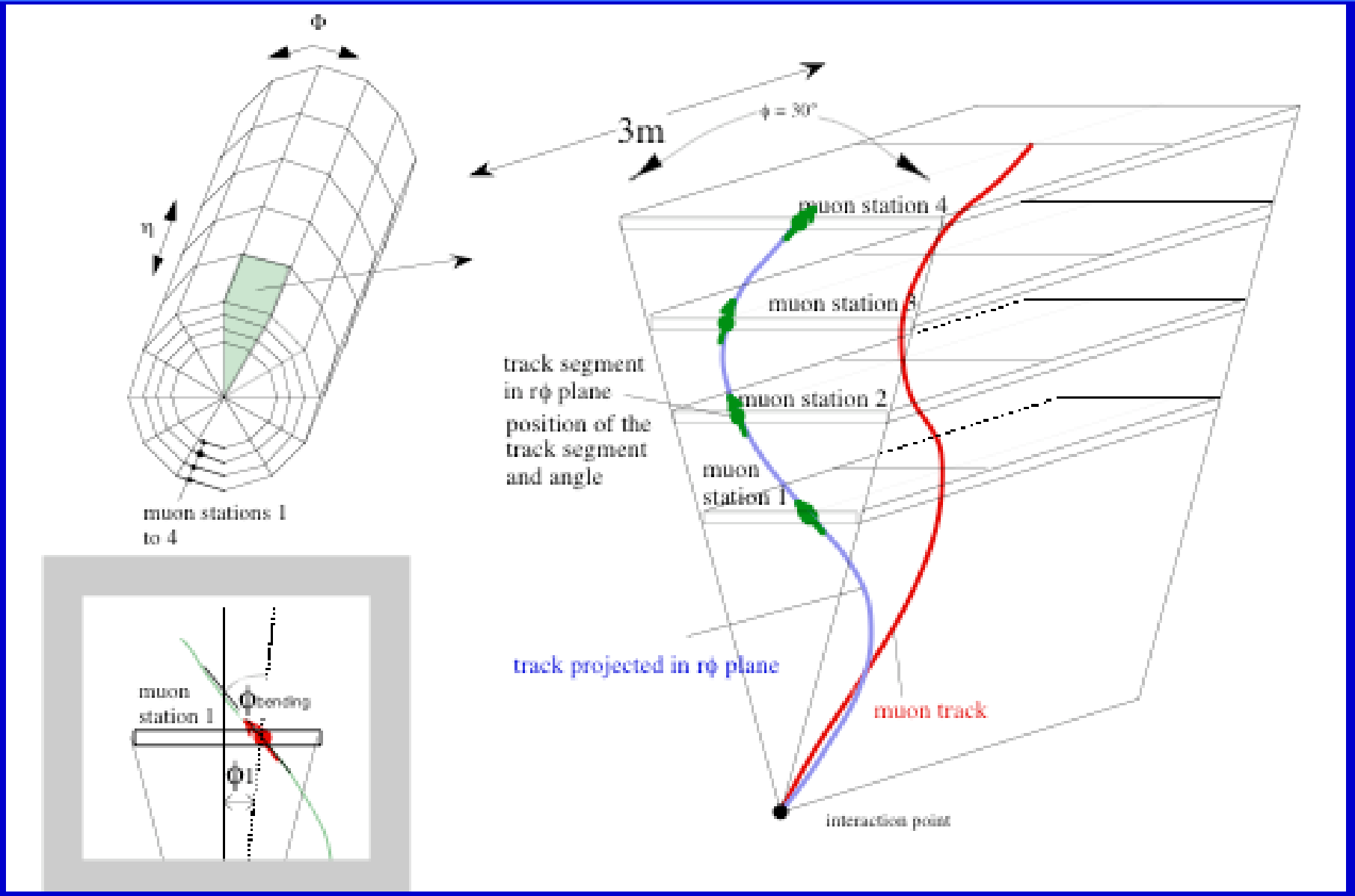
1 track segment
position (phi): 12 bits
angle (phi_b): 10 bits
quality code: 3 bits

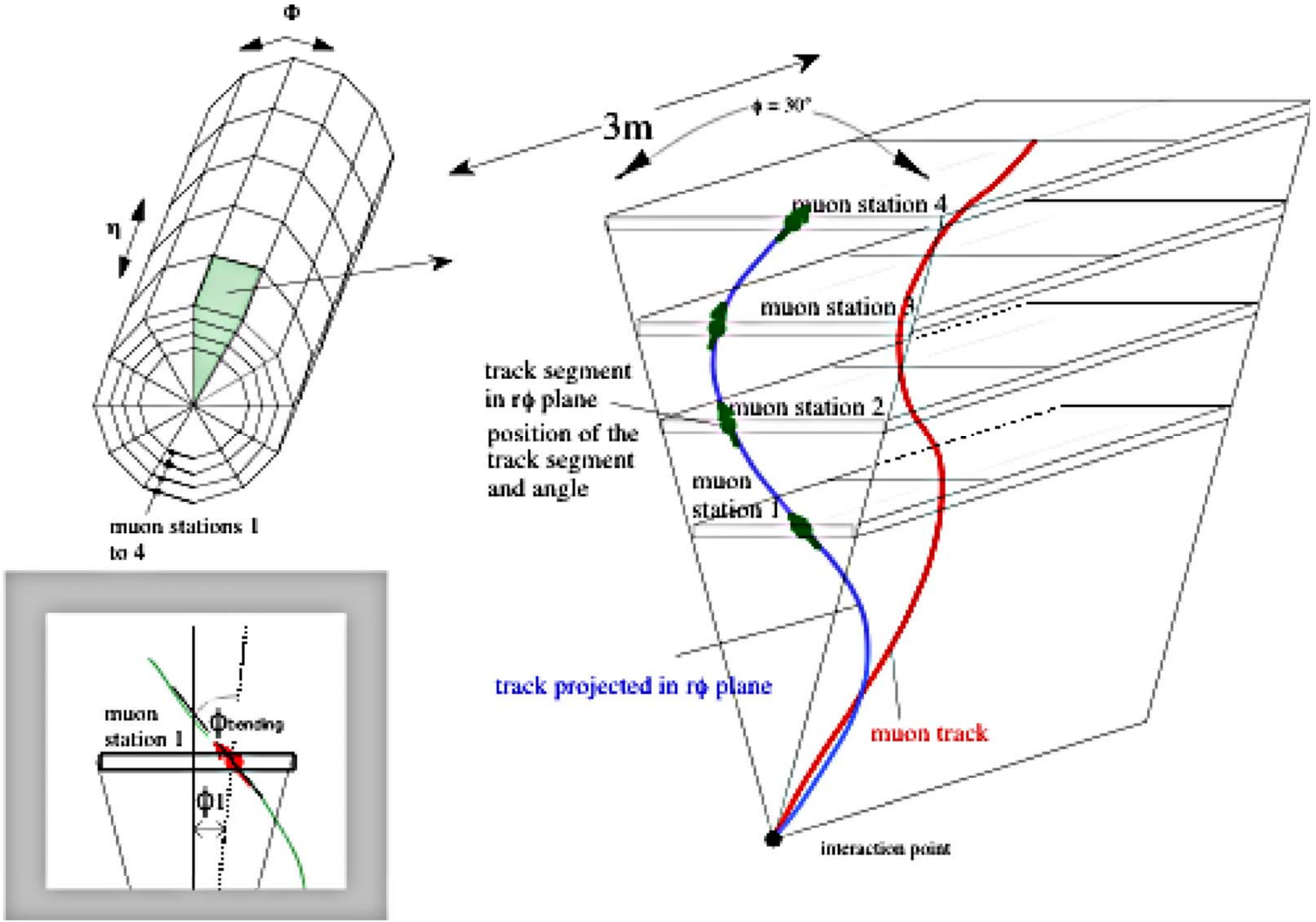
25 bits * 480 track segment = 12000 bits
12000 bits * 40 MHz = 480 Gbit/s

Muon track finder trigger

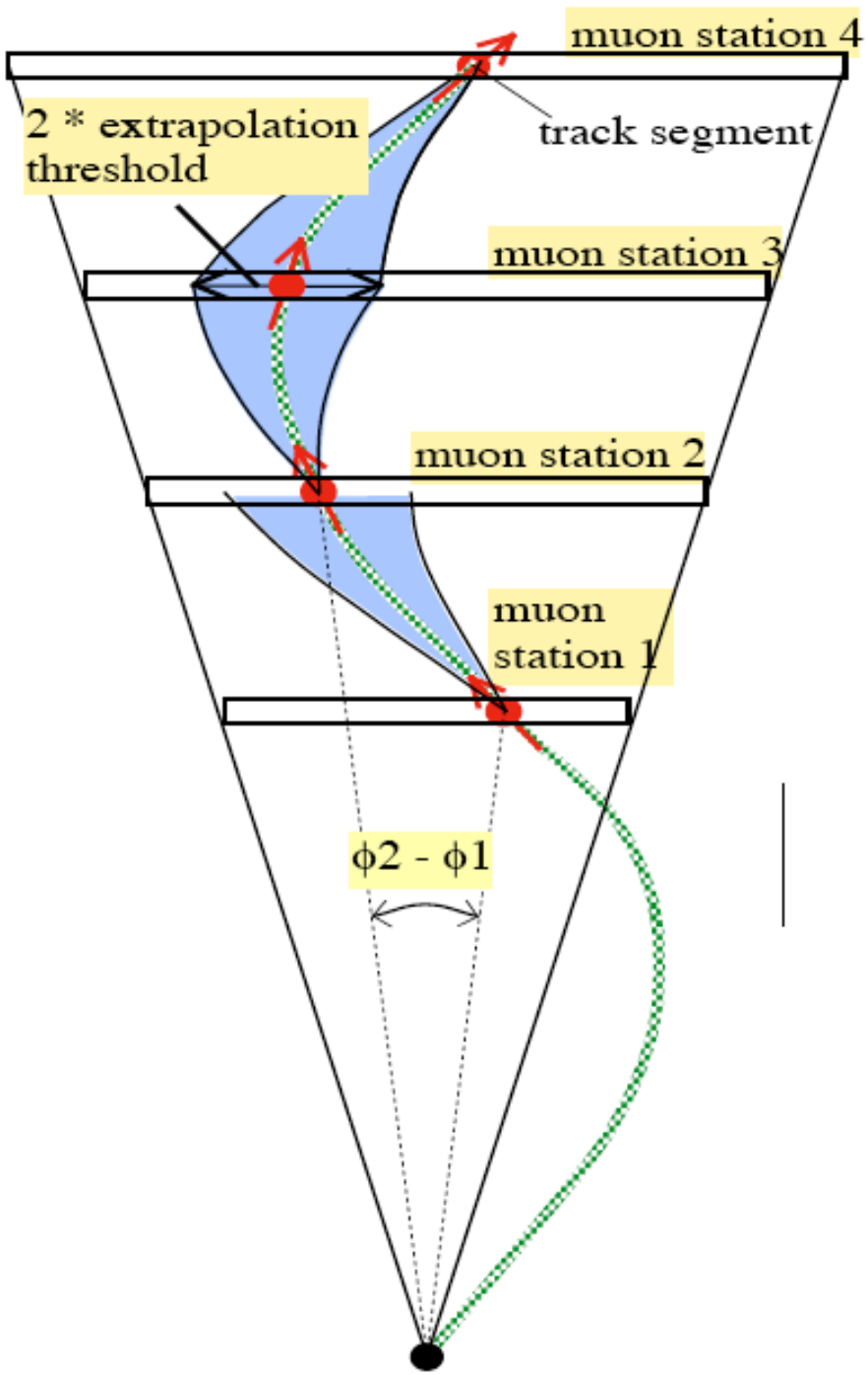
How?

Muon track finder trigger

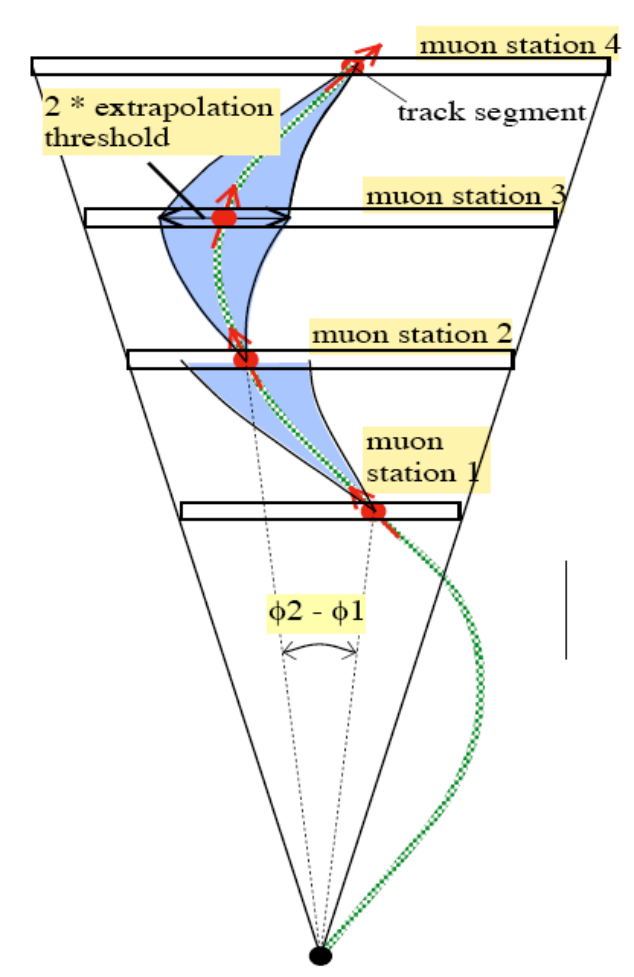


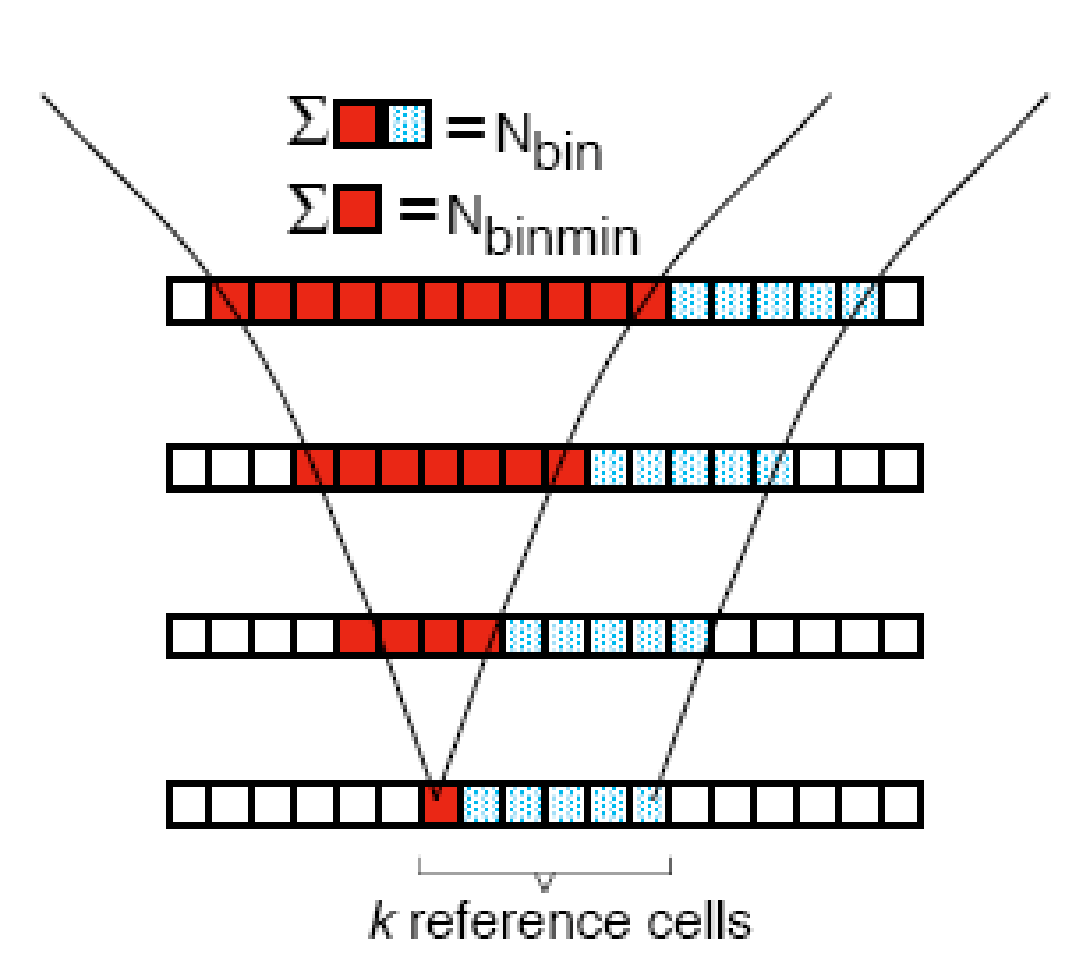

Φ
η
muon stations 1
to 4
3m
ϕ = 30°
muon station 4
muon station 3
track segment
in rϕ plane
position of the
track segment
and angle
muon station 2
muon
station 1
track projected in rϕ plane
muon track
interaction point
muon
station 1
ϕbending
ϕt

Muon track finder trigger

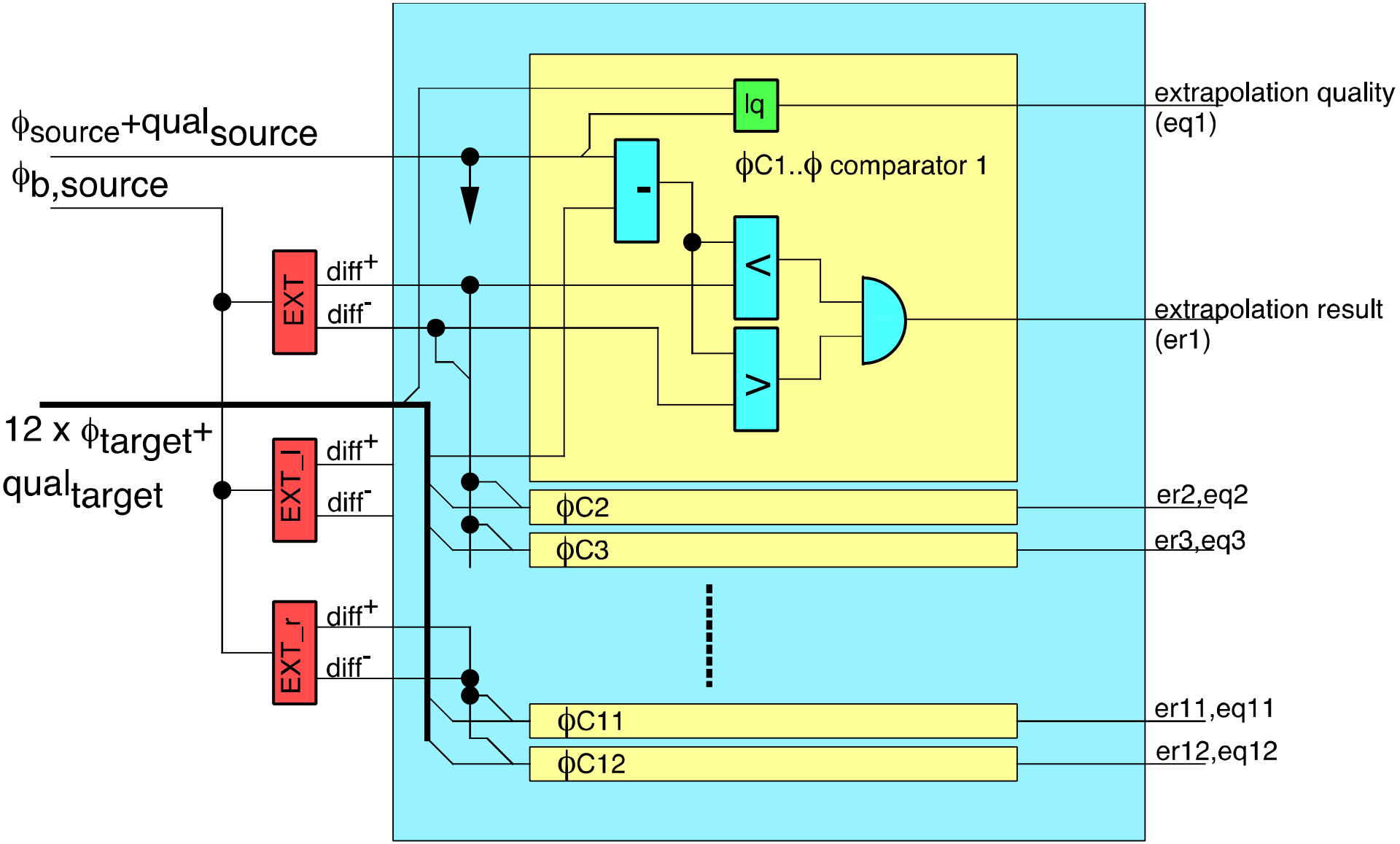


Muon track finder trigger

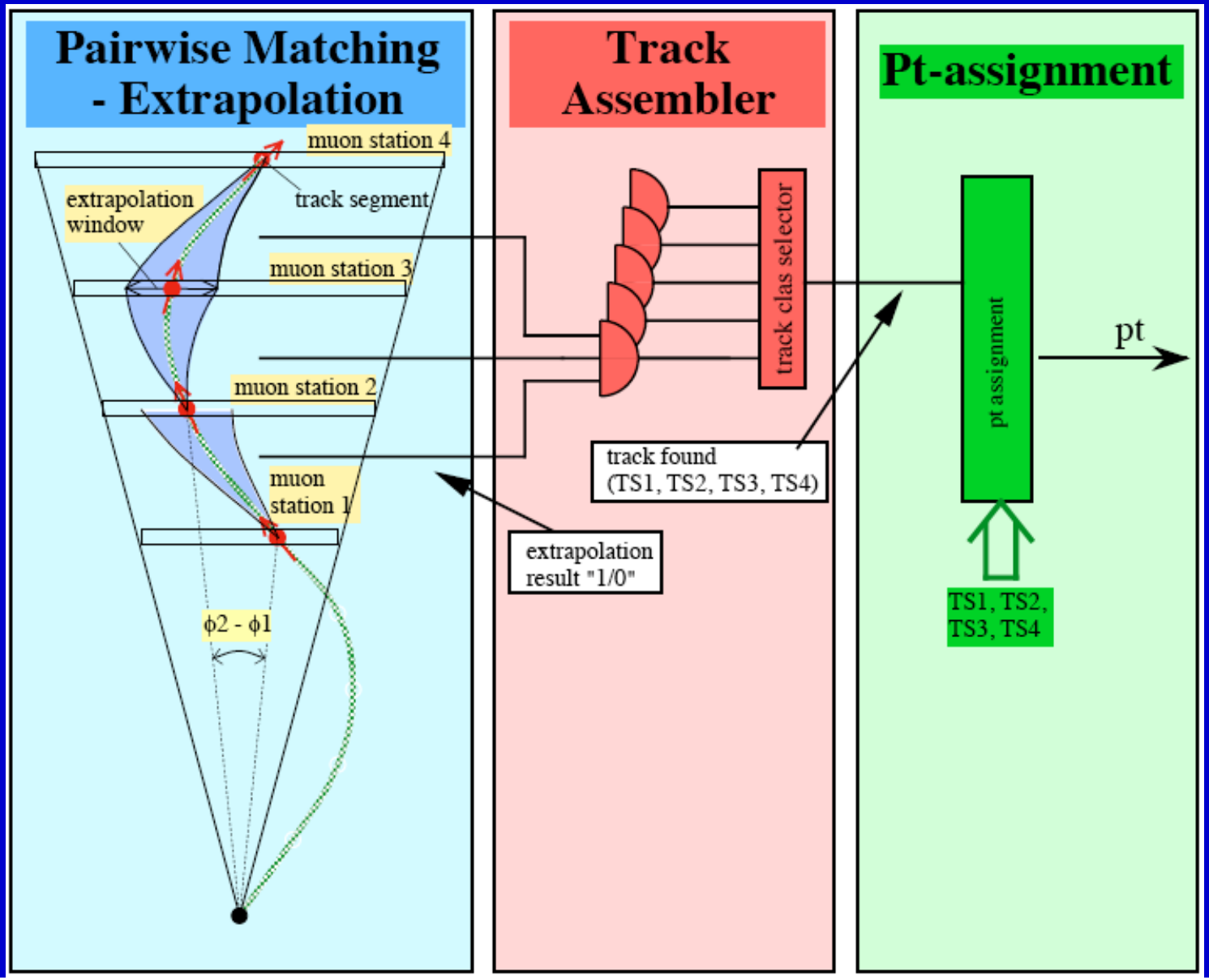




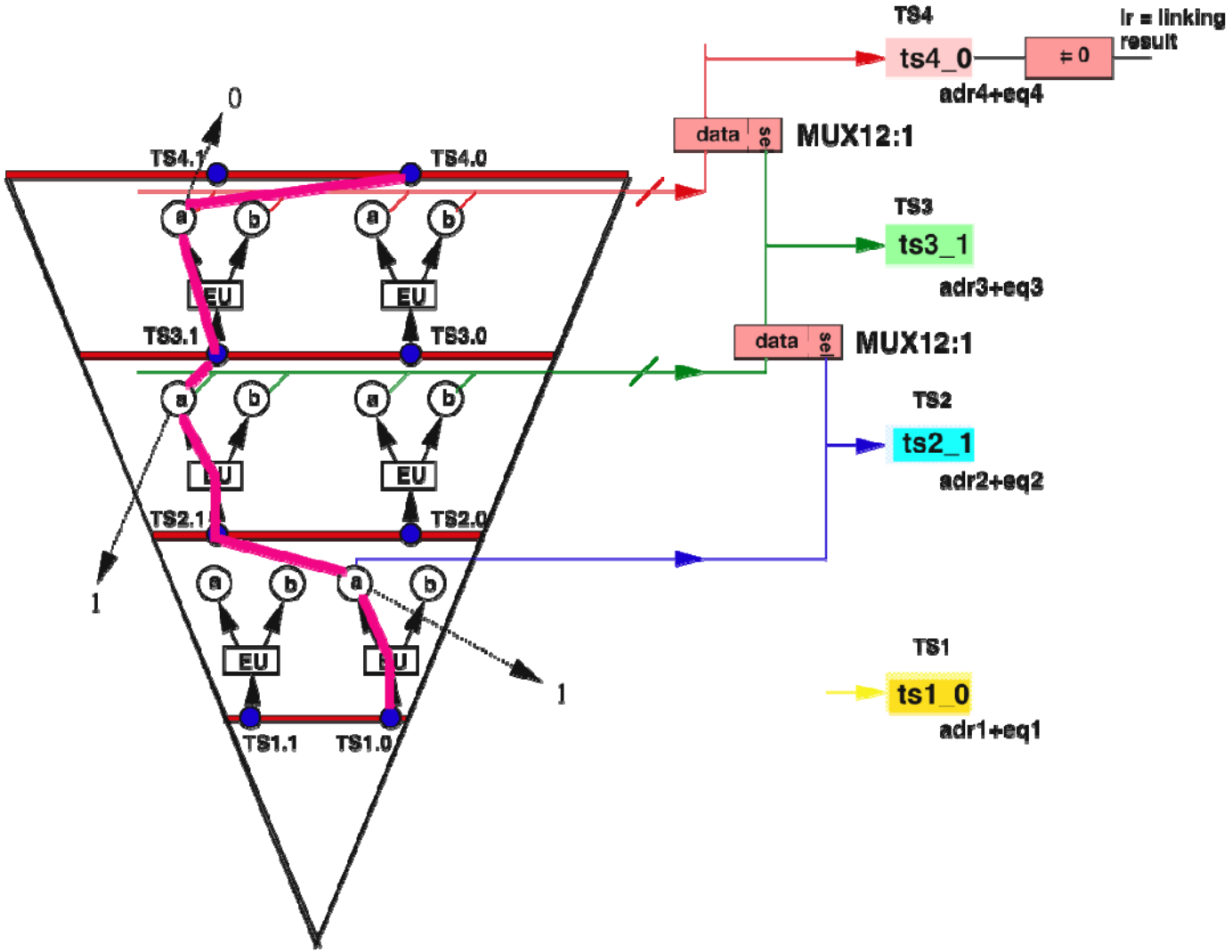
Muon track finder trigger



Muon track finder trigger

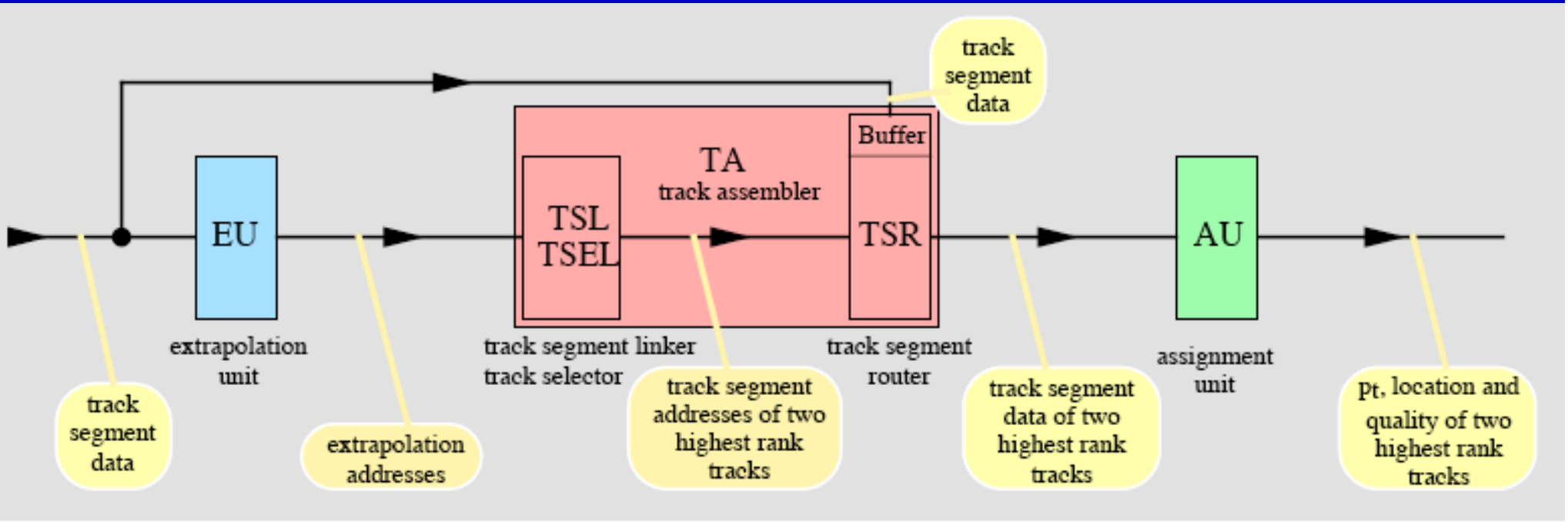


Muon track finder trigger



Result of all extrapolation units is 180 bits
-> data reduction
Track assembly unit is combinatorial and looks for the longest possible track combination

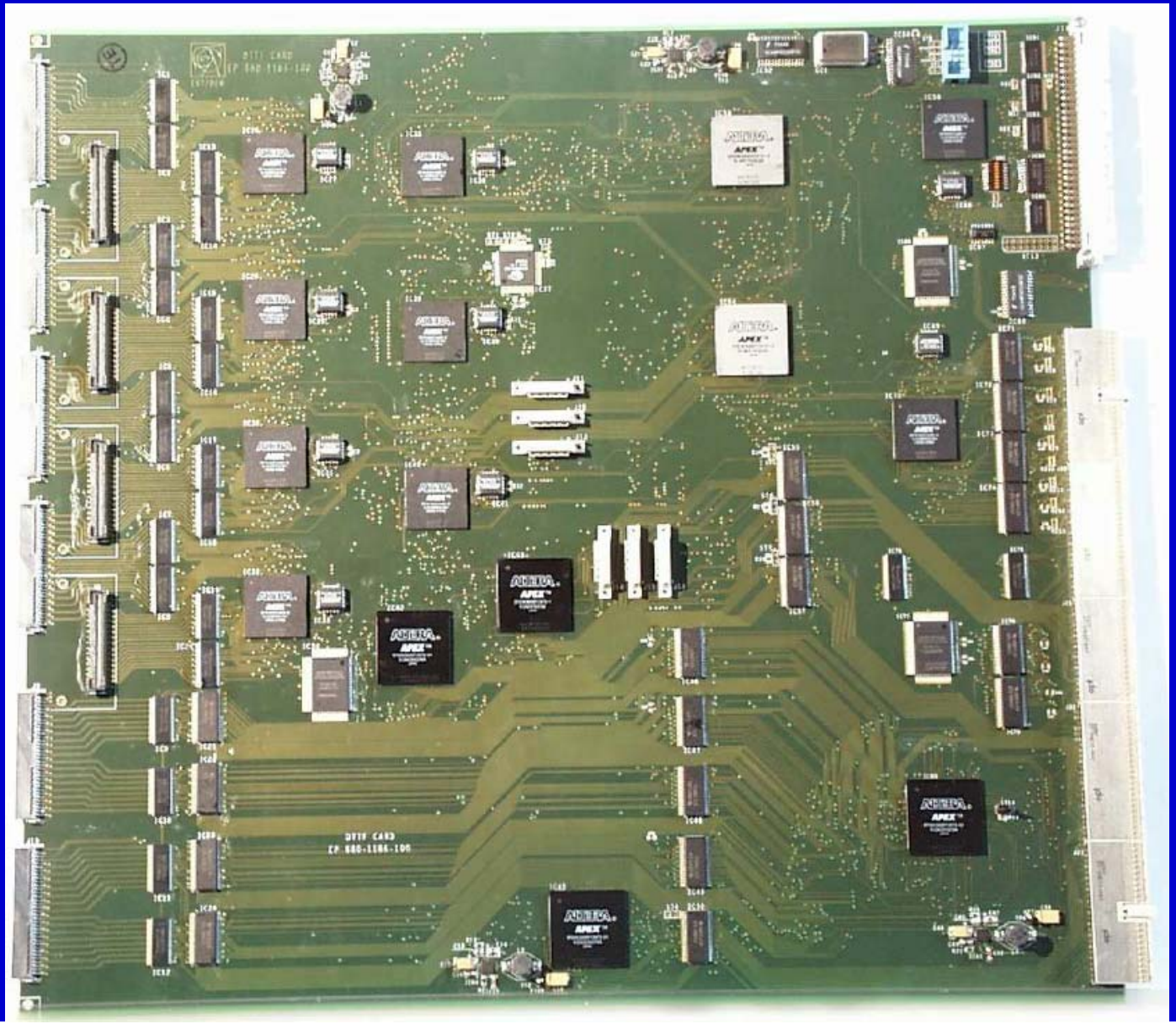
Muon track finder trigger



Parameter assignment unit: momentum (5 bits) based on difference in position of layer 1 and 2

Muon track finder trigger

Muon track finder trigger

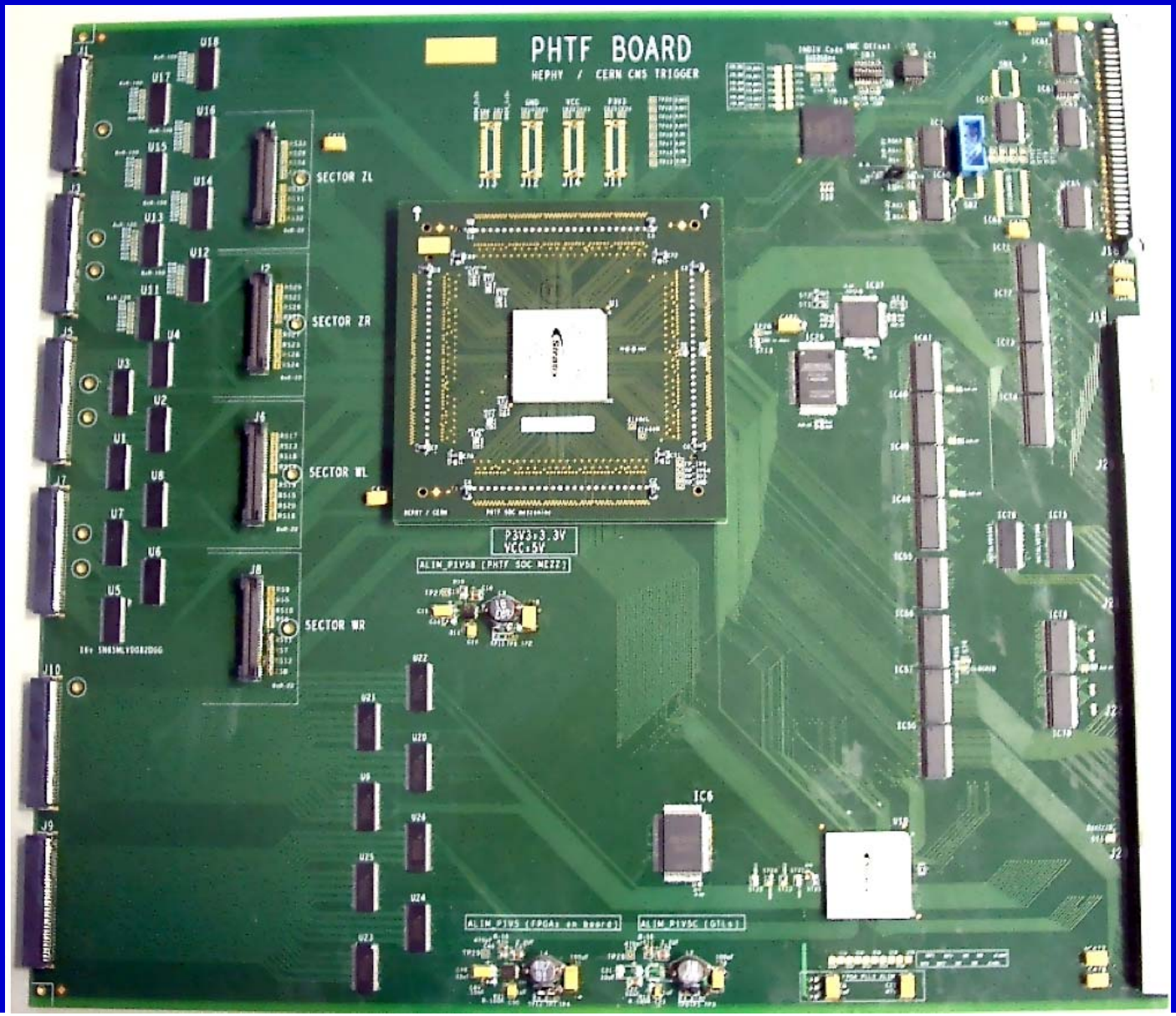


Muon track finder trigger

Extrapolation units: EP20k400EFC672
Data pipeline: 3 x EP1k100FC484
Track segment linker: EP20k300

16 layer PCB
no pin level back annotation
no board level simulation
Soldering problems with ball grid

Muon track finder trigger



Muon track finder trigger

All in EP1S40F1020C7

8 layer PCB
pin level back annotation
board level VHDL simulation
full JTAG boundary scan
FPGA on daughter card

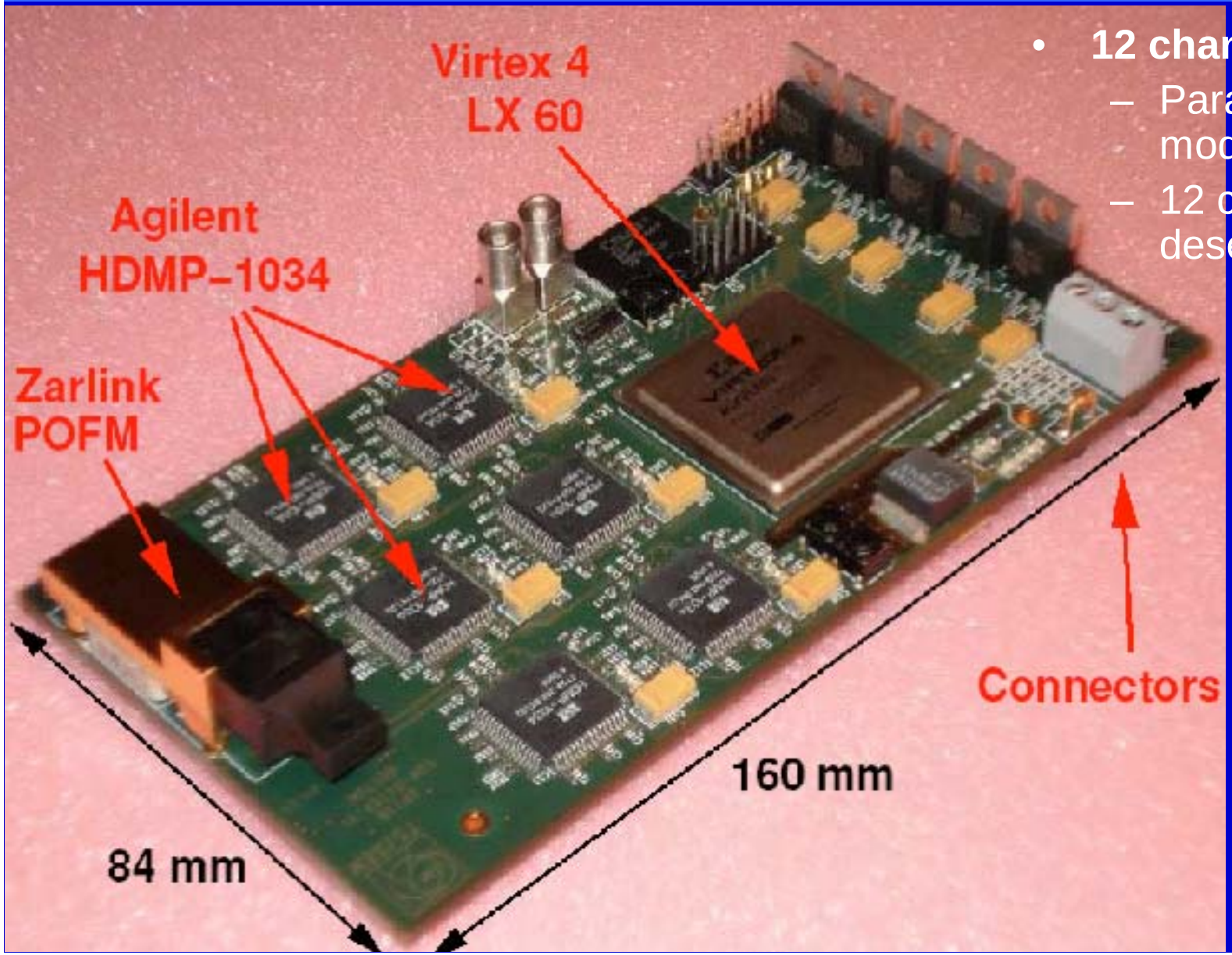
Muon track finder trigger

- **Conclusion track finder:**

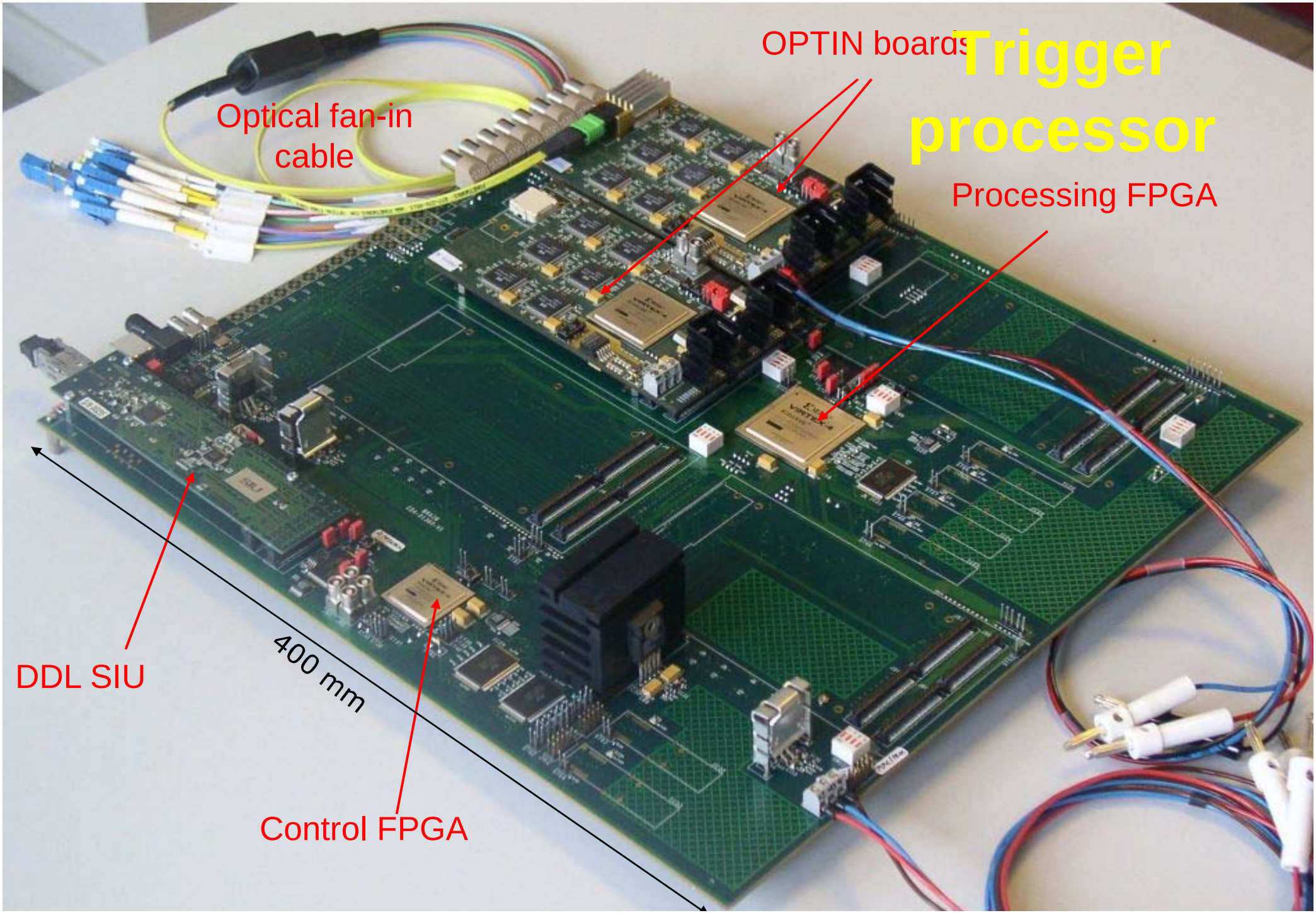
- **Data reduction**
- **Pipelining**
- **Feasibility study on possible algorithms**
- **Back annotation of Pins in FPGA after routing**
- **Full board – multiple FPGA VHDL simulation**
- **Stimulus files from (costumer) simulation**
- **Planning at FPGA level has impact on system implementation**

Example FPGA processors

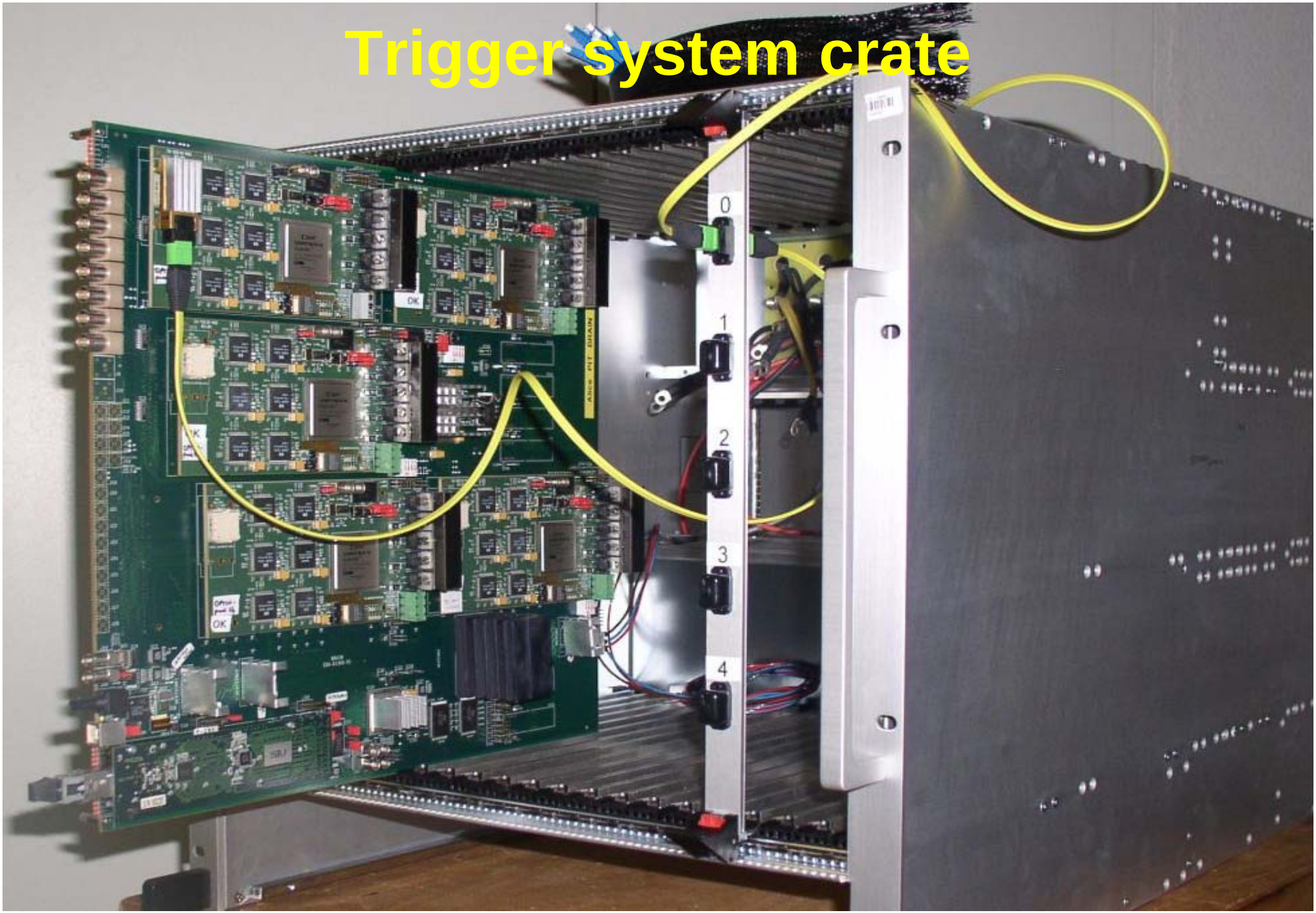
Processor board with optical inputs



- **12 channels**
  - Parallel optical receiver module
  - 12 closely packed G-link deserializer ASICs


Trigger processor
OPTIN boards
Optical fan-in cable
Processing FPGA
DDL SIU
400 mm
Control FPGA

Trigger system crate



Design cycle

Design cycle

- **System – Specifications**
- **Different approaches - possibilities**
  - ASICs, CAM -> FPGA
  - Pattern recognition / Analytical approach => Mixture => successive data reduction
- **Simulation - Feasibility - Forecast to future technologies**
- **Data flow simulation/calculation**
  - buffer sizes
  - dead times

Design cycle

- **Implementation scheme – propose technology independent architecture**
  - Do not push problems to a higher level - IO pins, PCB, system

- **Technology independent Simulation**
  - Full system: system input patterns – Qualification of data process
  - implement/integrate into system surrounding - work on FPGA code
  - Simulation together with environment
    - other FPGAs
    - input data

Design cycle

- **Implementation - technology dependent**

- **Selection of components**
  - Performance, features, evaluation, availability
  - price, age/phase in product cycle,
    - if very new -> support and access to high quantity difficult -> close connection to distributor

- **Define strategy on Maintenance and upgrades**
  - FPGA might get too full & slow after implementation of more and more functions
  - FPGA might get too old/obsolete during product cycle

Design cycle

- **FPGA simulation/synthesis/place&route/back-annotation**
- **Board Placing/routing**
  - FPGA -> board -> FPGA
  - FPGA Back annotation/Board level of pin position-Feedback on board layout
- **Functional/behavioral simulation of HDL code**
  - back annotated gate level after routing with board/system level
  - SEU simulation

Design cycle

- **Problems which are not solved on component level (ASIC/FPGA)**
  - are pushed to the system level, become expensive and time consuming

- **System level considerations ->**
  - System level simulation
  - Multi designer environment
  - Multi component environment

Example design

- **Prototype no internal design constraints on pin assignment for board layout -> 16 layer board ->**
  - with assignment clean and 8 layer board

- **Missing board level simulation with two FPGAs**
  - simulation of each FPGA is OK
    together setup and hold time violations
    board delay

- **Evolution of FPGA technology:**
  - more than 1 FPGA with board routing ->
  - 1 FPGA no board routing

Design cycle

- **Software/Hardware development must go hand in hand**
- **Debugging features in FPGAs/system/history/status**
- **Remote control is often required**
  - how to implement
  - always one FPGA not reprogrammable as communication processor

Design cycle

- **Board production**
  - JTAG boundary scan is mandatory for BGA
    - Full system JTAG especially with multiple FPGAs on board
    - reduces turn around time
    - gives proof of problems to manufacturer
    - X-ray tests are not always conclusive (example not even copper on pads)
  - Soldering problems with prototype series
  - Test points

Design cycle

- **Define strategy on Reliability**
  - which date may be corrupted and which data must not be corrupted
  - radiation, SEU, cosmic rays on ground level
  - sub micron ASICs/FPGA